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512Mb DDR2 SDRAM
EU RoHS Compliant Products

Data Sheet

Rev. E

Revision History		
Date	**Revision**	**Subjects (major changes since last revision)**
2015-11-01	A	Initialized Version
2016-03-01	B	Change to UniIC Format
2016-12-08	C	Add the “A3” grade product
2017-05-31	D	Add the “X” grade product
2017-09-05	E	Add the “A2” grade product Format review (2020-05)

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Contents

1 Overview

This chapter gives an overview of the 512Mbit Double-Data-Rate-Two SDRAM product family and describes its main characteristics.

1.1 Features

The 512Mbit Double-Data-Rate-Two SDRAM offers the following key features:

- 1.8 V ±0.1 V Power Supply
  1.8 V ±0.1 V (SSTL_18) compatible I/O
- DRAM organizations with x8, x16 data in/outputs
- Operating Comply with JEDEC DDR2 SDRAM standard
- Eight internal banks for concurrent operation
- Programmable CAS Latency: 3, 4, 5, 6, 7
- Programmable Burst Length: 4 and 8
- Differential clock inputs (CK and $\overline{CK}$)
- Bi-directional, differential data strobes (DQS and $\overline{DQS}$) are transmitted / received with data. Edge aligned with read data and center-aligned with write data.
- DLL aligns DQ and DQS transitions with clock
- $\overline{DQS}$ can be disabled for single-ended data strobe operation
- Commands entered on each positive clock edge, data and data mask are referenced to both edges of DQS
- Data masks (DM) for write data
- Posted CAS by programmable additive latency for better command and data bus efficiency
- Off-Chip-Driver impedance adjustment (OCD) and On-Die-Termination (ODT) for better signal quality
- Auto-Precharge operation for read and write bursts
- Auto-Refresh, Self-Refresh and power saving Power-Down modes
- Operating temperature range (T_{CASE})
  - Commercial, C(0 °C to 95 °C)
  - Industrial, I (-40 °C to 95 °C)
  - Automotive, A2(-40 °C to 105 °C)
  - Automotive, A3(-40 °C to 95 °C)
  - High-Rel, X (-55 °C to 125 °C)
- Average Refresh Period 7.8 µs at a T_{CASE} lower than 105°C, 3.9 µs between 105 °C and 125 °C
- Programmable self refresh rate via EMRS2 setting
- Full and reduced Strength Data-Output Drivers
- 1KB page size for ×8, 2KB page size for ×16
- Packages: PG-TFBGA-60 for x8 and PG-TFBGA-84 for x16

NOTE: Self Refresh Mode available on temperature less than 105°C (Tcase) only.

Table 1 - Performance Table

UniIC Speed Code			–19F	–25D	–25E	–3D	Unit	Note
DRAM Speed Grade		DDR2	–1066	–800	–800	–667		
CAS-RCD-RP latencies			7–7–7	5–5–5	6–6–6	5–5–5	t_{CK}	
Max. Clock Frequency	CL4	f_{CK4}	266	266	266	266	MHz	
	CL5	f_{CK5}	333	400	333	333	MHz	
	CL6	f_{CK6}	400	–	400	–	MHz	
	CL7	f_{CK7}	533	–	–	–	MHz	
Min. RAS-CAS-Delay		t_{RCD}	13.125	12.5	15	15	ns	
Min. Row Precharge Time		t_{RP}	13.125	12.5	15	15	ns	
Min. Row Active Time		t_{RAS}	45	45	45	45	ns	
Min. Row Cycle Time		t_{RC}	58.125	57.5	60	60	ns	3)
Precharge-All (8 banks) command period		t_{PREA}	15	15	17.5	18	ns	1)2)

1) This t_{PREA} value is the minimum value at which this chip will be functional.
2) Precharge-All command for an 8 bank device will equal to t_{RP} + 1 × t_{CK} or t_{nRP} + 1 × nCK, depending on the speed bin, where t_{nRP} = RU{ t_{RP} / $t_{CK(avg)}$ } and t_{RP} is the value for a single bank precharge.
3) READs and WRITEs with auto precharge are allowed to be issued before tRAS (MIN) is satisfied because tRAS lockout feature is supported in DDR2 SDRAM.

1.2 Description

The 512Mbit DDR2 SDRAM is a high-speed Double-Data-Rate- Two CMOS Synchronous DRAM device Containing 536,870,912 bits and internally configured as an octal bank DRAM.

The 512Mbit device is organized as 16 Mbit ×8 I/O ×4 banks or 8 Mbit ×16 I/O ×4 banks chip. These synchronous devices achieve high speed transfer rates starting at 400mb/sec/pin for general applications. See **Table 1** for performance figures.

The device is designed to comply with JEDEC DDR2 DRAM Standard key features:

1. Posted $\overline{\text{CAS}}$ with additive latency.
2. Write latency = read latency - 1.
3. Normal and weak strength data-output driver.
4. Off-Chip Driver (OCD) impedance adjustment.
5. On-Die Termination (ODT) function.

All of the control and address inputs are synchronized with a pair of externally supplied differential clocks. Inputs are latched at the cross point of differential clocks (CK rising and $\overline{\text{CK}}$ falling). All I/Os are synchronized with a single ended DQS or differential DQS-$\overline{\text{DQS}}$ pair in a source synchronous fashion.

A 14 bit address bus for ×8 organised components and a 13 bit address bus for ×16 components is used to convey row, column and bank address information in a $\overline{\text{RAS}}$- $\overline{\text{CAS}}$ multiplexing style.

The DDR2 device operates with a 1.8 V ±0.1 V power supply. An Auto-Refresh and Self-Refresh mode is provided along with various power-saving power-down modes.

The functionality described and the timing specifications included in this data sheet are for the DLL Enabled mode of operation.

The DDR2 SDRAM is available in TFBGA package.

Table 2 - Ordering Information for RoHS Compliant Products

Product Type[1)]	Org.	Speed	CAS-RCD-RP Latencies[2)3)4)]	Clock (MHz)	Package	Note[5)]
Commercial Temperature Range (0 °C~ +95 °C)						
DDR2-1066F (7-7-7)						
SCB18T512800AF-19F	×8	DDR2-1066F	7-7-7	533	PG-TFBGA-60	
SCB18T512160AF-19F	×16	DDR2-1066F	7-7-7	533	PG-TFBGA-84	
DDR2-800D (5-5-5)						
SCB18T512800AF-25D	×8	DDR2-800D	5-5-5	400	PG-TFBGA-60	
SCB18T512160AF-25D	×16	DDR2-800D	5-5-5	400	PG-TFBGA-84	
DDR2-800E (6-6-6)						
SCB18T512800AF-25E	×8	DDR2-800E	6-6-6	400	PG-TFBGA-60	
SCB18T512160AF-25E	×16	DDR2-800E	6-6-6	400	PG-TFBGA-84	
DDR2-667D (5-5-5)						
SCB18T512800AF-3D	×8	DDR2-667D	5-5-5	333	PG-TFBGA-60	
SCB18T512160AF-3D	×16	DDR2-667D	5-5-5	333	PG-TFBGA-84	
Industrial Temperature Range (-40 °C~ +95 °C)						
DDR2-1066F (7-7-7)						
SCB18T512800AF-19FI	×8	DDR2-1066F	7-7-7	533	PG-TFBGA-60	
SCB 18T512160AF-19FI	×16	DDR2-1066F	7-7-7	533	PG-TFBGA-84	
DDR2-800D (5-5-5)						
SCB18T512800AF-25DI	×8	DDR2-800D	5-5-5	400	PG-TFBGA-60	
SCB18T512160AF-25DI	×16	DDR2-800D	5-5-5	400	PG-TFBGA-84	
DDR2-800E (6-6-6)						
SCB18T512800AF-25EI	×8	DDR2-800E	6-6-6	400	PG-TFBGA-60	
SCB18T512160AF-25EI	×16	DDR2-800E	6-6-6	400	PG-TFBGA-84	
DDR2-667D (5-5-5)						
SCB18T512800AF-3DI	×8	DDR2-667D	5-5-5	333	PG-TFBGA-60	
SCB18T512160AF-3DI	×16	DDR2-667D	5-5-5	333	PG-TFBGA-84	
Automotive Temperature Range:A3 (-40 °C~ +95 °C)						
DDR2-1066F (7-7-7)						
SCB18T512800AF-19FA3	×8	DDR2-1066F	7-7-7	533	PG-TFBGA-60	
SCB18T512160AF-19FA3	×16	DDR2-1066F	7-7-7	533	PG-TFBGA-84	
DDR2-800D (5-5-5)						
SCB18T512800AF-25DA3	×8	DDR2-800D	5-5-5	400	PG-TFBGA-60	
SCB18T512160AF-25DA3	×16	DDR2-800D	5-5-5	400	PG-TFBGA-84	
DDR2-800E (6-6-6)						
SCB18T512800AF-25EA3	×8	DDR2-800E	6-6-6	400	PG-TFBGA-60	
SCB18T512160AF-25EA3	×16	DDR2-800E	6-6-6	400	PG-TFBGA-84	
DDR2-667D (5-5-5)						
SCB18T512800AF-3DA3	×8	DDR2-667D	5-5-5	333	PG-TFBGA-60	
SCB18T512160AF-3DA3	×16	DDR2-667D	5-5-5	333	PG-TFBGA-84	
High-Rel Temperature Range (-55 °C~ +125 °C)						
DDR2-1066F (7-7-7)						
SCB18T512800AF-19FX	×8	DDR2-1066F	7-7-7	533	PG-TFBGA-60	
SCB18T512160AF-19FX	×16	DDR2-1066F	7-7-7	533	PG-TFBGA-84	

Product Type[1)]	Org.	Speed	CAS-RCD-RP Latencies[2)3)4)]	Clock (MHz)	Package	Note[5)]
DDR2-800E (6-6-6)						
SCB18T512800AF-25DX	×8	DDR2-800D	5-5-5	400	PG-TFBGA-60	
SCB18T512160AF-25DX	×16	DDR2-800D	5-5-5	400	PG-TFBGA-84	
DDR2-667D (5-5-5)						
SCB18T512800AF-3DX	×8	DDR2-667D	5-5-5	333	PG-TFBGA-60	
SCB18T512160AF-3DX	×16	DDR2-667D	5-5-5	333	PG-TFBGA-84	
Automotive Temperature Range:A2 (-40 °C~ +105 °C)						
DDR2-1066F (7-7-7)						
SCB18T512800AF-19FA2	×8	DDR2-1066F	7-7-7	533	PG-TFBGA-60	
SCB18T512160AF-19FA2	×16	DDR2-1066F	7-7-7	533	PG-TFBGA-84	
DDR2-800E (6-6-6)						
SCB18T512800AF-25DA2	×8	DDR2-800D	5-5-5	400	PG-TFBGA-60	
SCB18T512160AF-25DA2	×16	DDR2-800D	5-5-5	400	PG-TFBGA-84	
DDR2-667D (5-5-5)						
SCB18T512800AF-3DA2	×8	DDR2-667D	5-5-5	333	PG-TFBGA-60	
SCB18T512160AF-3DA2	×16	DDR2-667D	5-5-5	333	PG-TFBGA-84	

1) For detailed information regarding product type of UniIC please see chapter "Product Nomenclature" of this data sheet.
2) CAS: Column Address Strobe
3) RCD: Row Column Delay
4) RP: Row Precharge
5) RoHS Compliant Product: Restriction of the use of certain hazardous substances (RoHS) in electrical and electronic equipment as defined in the directive 2002/95/EC issued by the European Parliament and of the Council of 27 January 2003. These substances include mercury, lead, cadmium, hexavalent chromium, polybrominated biphenyls and polybrominated biphenyl ethers. For more information please visit **http://www.unisemicon.com/**

2 Configuration

This chapter contains the chip configuration.

2.1 Configuration for TFBGA-60

The chip configuration of a DDR2 SDRAM is listed by function in **Table 3**. The abbreviations used in the Ball# and Buffer Type column are explained in **Table 4** and **Table 5** respectively.

Table 3 - Chip Configuration

Ball#	Name	Ball Type	Buffer Type	Function
Clock Signals ×8 Organizations				
E8	CK	I	SSTL	**Clock Signal CK, /CK**
F8	$\overline{\text{CK}}$	I	SSTL	
F2	CKE	I	SSTL	**Clock Enable**
Control Signals ×8 Organizations				
F7	$\overline{\text{RAS}}$	I	SSTL	**Row Address Strobe (RAS), Column Address Strobe (CAS), Write Enable (WE)**
G7	$\overline{\text{CAS}}$	I	SSTL	
F3	$\overline{\text{WE}}$	I	SSTL	
G8	$\overline{\text{CS}}$	I	SSTL	**Chip Select**
Address Signals ×8 Organizations				
G2	BA0	I	SSTL	**Bank Address Bus 1:0**
G3	BA1	I	SSTL	

Ball#	Name	Ball Type	Buffer Type	Function
H8	A0	I	SSTL	**Address Signal 13:0, Address Signal 10/Autoprecharge**
H3	A1	I	SSTL	
H7	A2	I	SSTL	
J2	A3	I	SSTL	
J8	A4	I	SSTL	
J3	A5	I	SSTL	
J7	A6	I	SSTL	
K2	A7	I	SSTL	
K8	A8	I	SSTL	
K3	A9	I	SSTL	
H2	A10	I	SSTL	
	AP	I	SSTL	
K7	A11	I	SSTL	
L2	A12	I	SSTL	
L8	A13	I	SSTL	
Data Signals ×8 Organizations				
C8	DQ0	I/O	SSTL	**Data Signal 3:0**
C2	DQ1	I/O	SSTL	
D7	DQ2	I/O	SSTL	
D3	DQ3	I/O	SSTL	
D1	DQ4	I/O	SSTL	**Data Signal 7:4**
D9	DQ5	I/O	SSTL	
B1	DQ6	I/O	SSTL	
B9	DQ7	I/O	SSTL	
Data Strobe ×8 Organizations				
B7	DQS	I/O	SSTL	**Data Strobe**
A8	$\overline{\text{DQS}}$	I/O	SSTL	
Data Strobe ×8 Organization				
B3	RDQS	O	SSTL	**Read Data Strobe**
A2	$\overline{\text{RDQS}}$	O	SSTL	
Data Mask ×8 Organizations				
B3	DM	I	SSTL	**Data Mask**

Ball#	Name	Ball Type	Buffer Type	Function
Power Supplies ×8 Organization				
A9, C1, C3, C7, C9	V_{DDQ}	PWR	–	**I/O Driver Power Supply**
A1, E9, H9, L1	V_{DD}	PWR	–	**Power Supply**
A7, B2, B8, D2, D8	V_{SSQ}	PWR	–	**I/O Driver Power Supply _Gnd**
A3, J1,E3, K9	V_{SS}	PWR	–	**Power Supply_Gnd**
E2	V_{REF}	AI	–	**I/O Reference Voltage**
E1	V_{DDL}	PWR	–	**Power Supply**
E7	V_{SSDL}	PWR	–	**Power Supply_Gnd**
Not Connected ×8 Organization				
L3, L7,G1	NC	NC	–	**Not Connected**
Other Balls ×8 Organizations				
F9	ODT	I	SSTL	**On-Die Termination Control**

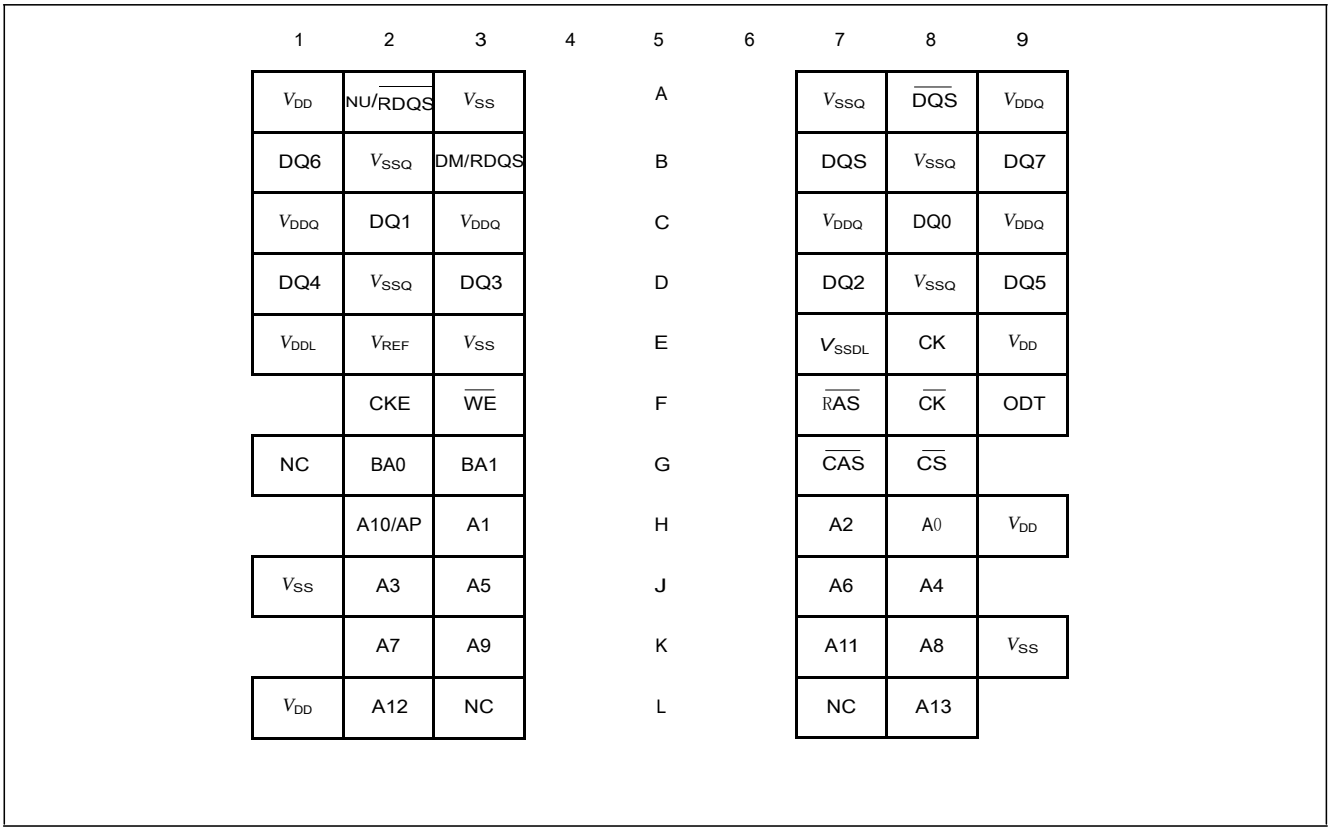
Table 4 - Abbreviations for Ball Type

Abbreviation	Description
I	Standard input-only ball. Digital levels.
O	Output. Digital levels.
I/O	I/O is a bidirectional input/output signal.
AI	Input. Analog levels.
PWR	Power
GND	Ground
NC	Not Connected

Table 5 - Abbreviations for Buffer Type

Abbreviation	Description
SSTL	Serial Stub Terminated Logic (SSTL_18)
LV-CMOS	Low Voltage CMOS
CMOS	CMOS Levels
OD	Open Drain. The corresponding ball has 2 operational states, active low and tristate, and allows multiple devices to share as a wire-OR.

Figure 1 - Chip Configuration for ×8 Components, TFBGA-60 (Top view)



Notes

1. *RDQS / $\overline{RDQS}$ are enabled by EMRS(1) command.*
2. *If RDQS / $\overline{RDQS}$ is enabled, the DM function is disabled*
3. *When enabled, RDQS & $\overline{RDQS}$ are used as strobe signals during reads.*
4. *V_{DDL} and V_{SSDL} are power and ground for the DLL.*

2.2 Configuration for TFBGA-84

The chip configuration of a DDR2 SDRAM is listed by function in **Table 6**. The abbreviations used in the Ball#/Buffer Type columns are explained in **Table 7** and **Table 8** respectively.

Table 6 - Configuration

Ball#	Name	Ball Type	Buffer Type	Function
Clock Signals ×16 Organization				
J8	CK	I	SSTL	**Clock Signal CK, /CK**
K8	$\overline{\text{CK}}$	I	SSTL	
K2	CKE	I	SSTL	**Clock Enable**
Control Signals ×16 Organization				
K7	$\overline{\text{RAS}}$	I	SSTL	**Row Address Strobe (RAS), Column Address Strobe (CAS), Write Enable (WE)**
L7	$\overline{\text{CAS}}$	I	SSTL	
K3	$\overline{\text{WE}}$	I	SSTL	
L8	$\overline{\text{CS}}$	I	SSTL	**Chip Select**
Address Signals ×16 Organization				
L2	BA0	I	SSTL	**Bank Address Bus 1:0**
L3	BA1	I	SSTL	
M8	A0	I	SSTL	**Address Signal 12:0, Address Signal 10/Autoprecharge**
M3	A1	I	SSTL	
M7	A2	I	SSTL	
N2	A3	I	SSTL	
N8	A4	I	SSTL	
N3	A5	I	SSTL	
N7	A6	I	SSTL	
P2	A7	I	SSTL	
P8	A8	I	SSTL	
P3	A9	I	SSTL	
M2	A10	I	SSTL	
	AP	I	SSTL	
P7	A11	I	SSTL	
R2	A12	I	SSTL	

Ball#	Name	Ball Type	Buffer Type	Function
Data Signals ×16 Organization				
G8	DQ0	I/O	SSTL	**Data Signal Lower Byte 7:0**
G2	DQ1	I/O	SSTL	
H7	DQ2	I/O	SSTL	
H3	DQ3	I/O	SSTL	
H1	DQ4	I/O	SSTL	
H9	DQ5	I/O	SSTL	
F1	DQ6	I/O	SSTL	
F9	DQ7	I/O	SSTL	
C8	DQ8	I/O	SSTL	**Data Signal Upper Byte 15:8**
C2	DQ9	I/O	SSTL	
D7	DQ10	I/O	SSTL	
D3	DQ11	I/O	SSTL	
D1	DQ12	I/O	SSTL	
D9	DQ13	I/O	SSTL	
B1	DQ14	I/O	SSTL	
B9	DQ15	I/O	SSTL	
Data Strobe ×16 Organization				
B7	UDQS	I/O	SSTL	**Data Strobe Upper Byte**
A8	$\overline{\text{UDQS}}$	I/O	SSTL	
F7	LDQS	I/O	SSTL	**Data Strobe Lower Byte**
E8	$\overline{\text{LDQS}}$	I/O	SSTL	
Data Mask ×16 Organization				
B3	UDM	I	SSTL	**Data Mask Upper Byte**
F3	LDM	I	SSTL	**Data Mask Lower Byte**
Power Supplies ×16 Organization				
J2	V_{REF}	AI	–	**I/O Reference Voltage**
A9, C1, C3, C7, C9, E9, G1, G3, G7, G9	V_{DDQ}	PWR	–	**I/O Driver Power Supply**
J1	V_{DDL}	PWR	–	**Power Supply**
A1, E1, J9, M9, R1	V_{DD}	PWR	–	**Power Supply**
A7,B2,B8, D2, D8, E7, F2, F8, H2,H8	V_{SSQ}	PWR	–	**I/O Driver Power Supply _Gnd**
J7	V_{SSDL}	PWR	–	**Power Supply_Gnd**
A3, E3, J3, N1, P9	V_{SS}	PWR	–	**Power Supply_Gnd**
Not Connected ×16 Organization				
A2, E2, L1,R3, R7, R8	NC	NC	–	**Not Connected**
Other Balls ×16 Organization				
K9	ODT	I	SSTL	**On-Die Termination Control**

Table 7 - Abbreviations for Ball Type

Abbreviation	Description
I	Standard input-only ball. Digital levels.
O	Output. Digital levels.
I/O	I/O is a bidirectional input/output signal.
AI	Input. Analog levels.
PWR	Power
GND	Ground
NC	Not Connected

Table 8 - Abbreviations for Buffer Type

Abbreviation	Description
SSTL	Serial Stub Terminated Logic (SSTL_18)
LV-CMOS	Low Voltage CMOS
CMOS	CMOS Levels
OD	Open Drain. The corresponding ball has 2 operational states, active low and tristate, and allows multiple devices to share as a wire-OR.

Figure 2 - Chip Configuration for x16 Components, TFBGA–84 (Top view)

1	2	3	4	5	6	7	8	9
V_{DD}	NC	V_{SS}		A		V_{SSQ}	$\overline{UDQS}$	V_{DDQ}
DQ14	V_{SSQ}	UDM		B		UDQS	V_{SSQ}	DQ15
V_{DDQ}	DQ9	V_{DDQ}		C		V_{DDQ}	DQ8	V_{DDQ}
DQ12	V_{SSQ}	DQ11		D		DQ10	V_{SSQ}	DQ13
V_{DD}	NC	V_{SS}		E		V_{SSQ}	$\overline{LDQS}$	V_{DDQ}
DQ6	V_{SSQ}	LDM		F		LDQS	V_{SSQ}	DQ7
V_{DDQ}	DQ1	V_{DDQ}		G		V_{DDQ}	DQ0	V_{DDQ}
DQ4	V_{SSQ}	DQ3		H		DQ2	V_{SSQ}	DQ5
V_{DDL}	V_{REF}	V_{SS}		J		VSSDL	CK	V_{DD}
	CKE	$\overline{WE}$		K		$\overline{RAS}$	$\overline{CK}$	ODT
NC	BA0	BA1		L		$\overline{CAS}$	$\overline{CS}$	
	A10/AP	A1		M		A2	A0	V_{DD}
V_{SS}	A3	A5		N		A6	A4	
	A7	A9		P		A11	A8	V_{SS}
V_{DD}	A12	NC		R		NC	NC	

Notes

1. *UDQS/$\overline{UDQS}$ is data strobe for DQ[15:8], LDQS/$\overline{LDQS}$ is data strobe for DQ[7:0]*
2. *LDM is the data mask signal for DQ[7:0], UDM is the data mask signal for DQ[15:8]*
3. *V_{DDL} and V_{SSDL} are power and ground for the DLL.*

2.3 Addressing

This chapter describes the DDR2 SDRAM addressing.

Table 9 - Addressing

Configuration	64 Mb x 8[1)]	32 Mb x16[2)]	Note
Bank Address	BA[1:0]	BA[1:0]	
Number of Banks	4	4	
Auto Precharge	A10 / AP	A10 / AP	
Row Address	A[13:0]	A[12:0]	
Column Address	A[9:0]	A[9:0]	
Number of Column Address Bits	10	10	3)
Number of I/Os	8	16	
Page Size [Bytes]	1024 (1 K)	2048 (2 K)	4)

1) Referred to as 'org'
2) Referred to as 'org'
3) Referred to as 'colbits'
4) PageSize = $2^{colbits} \times org/8$ [Bytes]

3 Functional Description

This chapter contains the functional description.

3.1 Power-up and initialization sequence

The following sequence is required for Power-up and Initialization.

1) Either one of the following sequence is required for Power-up.

a1) While applying power, attempt to maintain CKE below 0.2 x VDDQ and ODT*1 at a LOW state (all other inputs may be undefined.) The VDD voltage ramp time must be no greater than 200 ms from when VDD ramps from 300 mV to VDD min; and during the VDD voltage ramp, |VDD-VDDQ| ≤ 0.3 volts. Once the ramping of the supply voltages is complete (when VDDQ crosses VDDQ min), the supply voltage specifications provided in section 5.2, table 20 Recommended DC operating conditions (SSTL_1.8), prevail.
- VDD, VDDL and VDDQ are driven from a single power converter output, AND
- VTT is limited to 0.95 V max, AND
- Vref tracks VDDQ/2, VREF must be within +/- 300 mV with respect to VDDQ/2 during supply ramp time.
- VDDQ ≥ VREF must be met at all times.

a2) While applying power, attempt to maintain CKE below 0.2 x VDDQ and ODT*1 at a LOW state, all other inputs may be undefined, voltage levels at I/Os and outputs must be less than VDDQ during voltage ramp time to avoid DRAM latch-up. During the ramping of the supply voltages, VDD ≥ VDDL ≥ VDDQ must be maintained and is applicable to both AC and DC levels until the ramping of the supply voltages is complete, which is when VDDQ crosses VDDQ min. Once the ramping of the supply voltages is complete, the supply voltage specifications provided in section 5.2, table 20 Recommended DC operating conditions (SSTL_1.8), prevail.
- Apply VDD/VDDL before or at the same time as VDDQ.
- VDD/VDDL voltage ramp time must be no greater than 200 ms from when VDD ramps from 300 mV to VDD min
- Apply VDDQ before or at the same time as VTT.
- The VDDQ voltage ramp time from when VDD min is achieved on VDD to when VDDQ min is achieved on VDDQ must be no greater than 500 ms.

(Note: While VDD is ramping, current may be supplied from VDD through the DRAM to VDDQ.)
- Vref must track VDDQ/2, Vref must be within +/- 300 mv with respect to VDDQ/2 during supply ramp time.
- VDDQ ≥ VREF must be met at all times.
- Apply VTT.
- The VTT voltage ramp time from when VDDQ min is achieved on VDDQ to when VTT min is achieved on VTT must be no greater than 500 ms.

2) Start clock and maintain stable condition.

3) For the minimum of 200 us after stable power (VDD, VDDL, VDDQ, VREF and VTT are between their minimum and maximum values as stated in section 5.2, table 20 Recommended DC operating conditions (SSTL_1.8)) and stable clock (CK, CK), then apply NOP or Deselect & take CKE HIGH.

4) Wait minimum of 400 ns then issue precharge all command. NOP or Deselect applied during 400 ns period.

5) Issue an EMRS command to EMR(2). (To issue EMRS command to EMR(2), provide LOW to BA0 and BA2, HIGH to BA1.)

6) Issue an EMRS command to EMR(3). (To issue EMRS command to EMR(3), provide LOW to BA2, HIGH to BA0 and BA1.)

7) Issue EMRS to enable DLL. (To issue DLL Enable command, provide LOW to A0, HIGH to BA0 and LOW to BA1-BA2 and A13-A15. And A9=A8=A7=LOW must be used when issuing this command.)

8) Issue a Mode Register Set command for DLL reset.
(To issue DLL Reset command, provide HIGH to A8 and LOW to BA0-BA2, and A13-A15.)

9) Issue a precharge all command.

10) Issue 2 or more auto-refresh commands.

11) Issue a MRS command with LOW to A8 to initialize device operation. (i.e. to program operating parameters

12) At least 200 clocks after step 8), execute OCD Calibration (Off Chip Driver impedance adjustment). If OCD calibration is not used, EMRS to EMR(1) to set OCD Calibration Default (A9=A8=A7=HIGH) followed by EMRS to EMR(1) to exit OCD Calibration Mode (A9=A8=A7=LOW) must be issued with other operating parameters of EMR(1).

13) The DDR2 SDRAM is now ready for normal operation.

*1: To guarantee ODT off, VREF must be valid and a LOW level must be applied to the ODT pin.

3.2 Mode Register Set (MRS)

The mode register stores the data for controlling the various operating modes of DDR2 SDRAM.

BA2	BA1	BA0	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0
0[1)]	0	0	0[1)]	PD	WR			DLL	TM	CL			BT	BL		

Table 10 - Mode Register Definition, $BA_{2:0} = 000_B$

Field	Bits	Description
PD	12	**Active Power-Down Mode Select** 0_B **PD** Fast exit 1_B **PD** Slow exit
WR	[11:9]	**Write Recovery**[2)] *Note: All other bit combinations are illegal.* 001_B **WR** 2 010_B **WR** 3 011_B **WR** 4 100_B **WR** 5 101_B **WR** 6 110_B **WR** 7 111_B **WR** 8
DLL	8	**DLL Reset** 0_B **DLL** No 1_B **DLL** Yes
TM	7	**Test Mode** 0_B **TM** Normal Mode 1_B **TM** Vendor specific test mode

Field	Bits	Description
CL	[6:4]	**CAS Latency**[3)] *Note: All other bit combinations are illegal.* 011_B **CL** 3 100_B **CL** 4 101_B **CL** 5 110_B **CL** 6 111_B **CL** 7
BT	3	**Burst Type** 0_B **BT** Sequential 1_B **BT** Interleaved
BL	[2:0]	**Burst Length** *Note: All other bit combinations are illegal.* 010_B **BL** 4 011_B **BL** 8

1) BA2 and A13 are reserved for future use and must be set to 0 when programming the MR.
2) Number of clock cycles for write recovery during auto-precharge. WR in clock cycles is calculated by dividing t_{WR} (in ns) by t_{CK} (in ns) and rounding up to the next integer: WR [cycles] $\geq t_{WR}$ (ns) / t_{CK} (ns). The mode register must be programmed to fulfill the minimum requirement for the analogue t_{WR} timing. WR_{MIN} is determined by $t_{CK.MAX}$ and WR_{MAX} is determined by $t_{CK.MIN}$.3) speed bin determined.
3) speed bin determined.

3.3 Extended Mode Register EMR(1)

The Extended Mode Register EMR(1) stores the data for enabling or disabling the DLL, output driver strength, additive latency, OCD program, ODT, DQS and output buffers disable, RDQS and RDQS enable.

BA2	BA1	BA0	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0
0[1)]	0	1	0[1)]	Qoff	RDQS	$\overline{DQS}$	OCD Program			Rtt	AL			Rtt	DIC	DLL

Table 11 - Extended Mode Register Definition, $BA_{2:0} = 001_B$

Field	Bits	Description
Qoff	12	**Output Disable** [5)] 0_B **QOff** Output buffers enabled 1_B **QOff** Output buffers disabled
RDQS	11	**Read Data Strobe Output (RDQS, $\overline{RDQS}$)** [6)] 0_B **RDQS** Disable 1_B **RDQS** Enable
$\overline{DQS}$	10	**Complement Data Strobe (DQS Output)** 0_B $\overline{DQS}$ Enable 1_B $\overline{DQS}$ Disable
OCD Program	[9:7]	**Off-Chip Driver Calibration Program** 000_B **OCD** OCD calibration mode exit, maintain setting 001_B **OCD** Drive (1) 010_B **OCD** Drive (0) 100_B **OCD** Adjust mode [3)] 111_B **OCD** OCD calibration default [4)]
AL	[5:3]	**Additive Latency** *Note: All other bit combinations are illegal.* 000_B **AL** 0 001_B **AL** 1 010_B **AL** 2 011_B **AL** 3 100_B **AL** 4 101_B **AL** 5 110_B **AL** 6

Field	Bits	Description
R_{TT}	6,2	**Nominal Termination Resistance of ODT** 00_B **RTT** ∞ (ODT disabled) 01_B **RTT** 75 Ohm 10_B **RTT** 150 Ohm 11_B **RTT** 50 Ohm [2)]
DIC	1	**Off-chip Driver Impedance Control** 0_B **DIC** Full (Driver Size = 100%) 1_B **DIC** Reduced
DLL	0	**DLL Enable** 0_B **DLL** Enable 1_B **DLL** Disable

1) BA2 and A13 are reserved for future use and must be set to 0 when programming the EMR(1).
2) Optional for DDR2-400/533/667, mandatory for DDR2-800.
3) When Adjust mode is issued, AL from previously set value must be applied.
4) After setting to default, OCD calibration mode needs to be exited by setting A9-A7 to 000.
5) Output disabled - DQs, DQSs, $\overline{\text{DQSs}}$, RDQS, $\overline{\text{RDQS}}$. This feature is used in conjunction with DIMM IDD measurements when IDDQ is not desired to be included.
6) If RDQS is enabled, the DM function is disabled. RDQS is active for reads and don't care for writes.

3.4 Extended Mode Register EMR(2)

The Extended Mode Registers EMR(2) control refresh related feature.

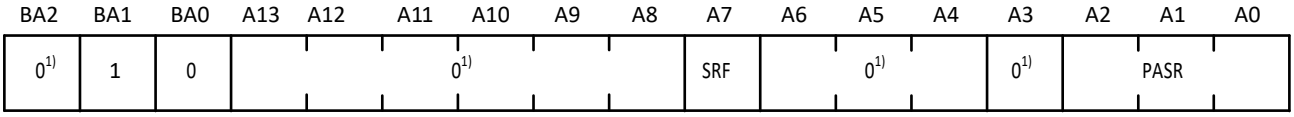


Table 12 - EMR(2) Programming Extended Mode Register Definition, $B_{A2:0}=010_B$

Field	Bits	Description
SRF	7	**Address Bus, High Temperature Self Refresh Rate for T_{CASE} > 105 ℃** 0_B **A7** disable 1_B **A7** enable [2)]
PASR	[2:0]	**Partial Self Refresh for 8 banks**[3)] 000_B Full array (Banks 000_B - 111_B) 001_B Half Array(Banks 000_B - 011_B) 010_B Quarter Array(Banks 000_B - 001_B) 011_B 1/8th array (Banks 000_B) 100_B 3/4 array(Banks 010_B - 111_B) 101_B Half array(Banks 100_B - 111_B) 110_B Quarter array(Banks 110_B - 111_B) 111_B 1/8th array(Banks 111_B)

1) BA2 and A6-A3, A13-A8 are reserved for future use and must be set to 0 when programming the EMR(2).
2) When DRAM is operated at 105°C ≤ TCase ≤ 125°C the extended self refresh rate must be enabled by setting bit A7 to 1 before the self refresh mode can be entered.
3) If PASR (Partial Array Self Refresh) is enabled, data located in areas of the array beyond the specified self refresh location may get lost if self refresh is entered. During non-self-refresh operation, data integrity will be maintained if *t*REFI conditions are met.

3.5 Extended Mode Register EMR(3)

The Extended Mode Register EMR(3) is reserved for future use and all bits except BA0 and BA1 must be programmed to 0 when setting the mode register during initialization.

Table 13 - EMR(3) Programming Extended Mode Register Definition, $BA_{2:0}=011_B$

BA2	BA1	BA0	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0
0[1)]	1	1	0[1)]													

1) All bits in EMR(3) except BA0 and BA1 are reserved for future use and must be set to 0 when programming the EMR(3).

3.6 Burst Mode Operation

Table 14 - Burst Length and Sequence

Burst Length	Starting Address (A2 A1 A0)	Sequential Addressing (decimal)	Interleave Addressing (decimal)
4	× 0 0	0, 1, 2, 3	0, 1, 2, 3
	× 0 1	1, 2, 3, 0	1, 0, 3, 2
	×1 0	2, 3, 0, 1	2, 3, 0, 1
	×1 1	3, 0, 1, 2	3, 2, 1, 0
8	0 0 0	0, 1, 2, 3, 4, 5, 6, 7	0, 1, 2, 3, 4, 5, 6, 7
	0 0 1	1, 2, 3, 0, 5, 6, 7, 4	1, 0, 3, 2, 5, 4, 7, 6
	0 1 0	2, 3, 0, 1, 6, 7, 4, 5	2, 3, 0, 1, 6, 7, 4, 5
	0 1 1	3, 0, 1, 2, 7, 4, 5, 6	3, 2, 1, 0, 7, 6, 5, 4
	1 0 0	4, 5, 6, 7, 0, 1, 2, 3	4, 5, 6, 7, 0, 1, 2, 3
	1 0 1	5, 6, 7, 4, 1, 2, 3, 0	5, 4, 7, 6, 1, 0, 3, 2
	1 1 0	6, 7, 4, 5, 2, 3, 0, 1	6, 7, 4, 5, 2, 3, 0, 1
	1 1 1	7, 4, 5, 6, 3, 0, 1, 2	7, 6, 5, 4, 3, 2, 1, 0

4 Truth Tables

The truth tables in this chapter summarize the commands and the signal coding to control a standard Double-Data-Rate-Two SDRAM.

Table 15 - Command Truth Table

Function	CKE		CS	RAS	CAS	WE	BA0 BA1 BA2	A[13:11]	A10	A[9:0]	Note[1)2)3)]
	Previous Cycle	Current Cycle									
(Extended) Mode Register Set	H	H	L	L	L	L	BA	OP Code			4)5)6)
Auto-Refresh	H	H	L	L	L	H	X	X	X	X	4)
Self-Refresh Entry	H	L	L	L	L	H	X	X	X	X	4)7)
Self-Refresh Exit	L	H	H	X	X	X	X	X	X	X	4)7)8)
			L	H	H	H					
Single Bank Precharge	H	H	L	L	H	L	BA	X	L	X	4)5)
Precharge all Banks	H	H	L	L	H	L	X	X	H	X	4)5)
Bank Activate	H	H	L	L	H	H	BA	Row Address			4)5)
Write	H	H	L	H	L	L	BA	Column	L	Column	4)5)9)
Write with Auto-Precharge	H	H	L	H	L	L	BA	Column	H	Column	4)5)9)
Read	H	H	L	H	L	H	BA	Column	L	Column	4)5)9)
Read with Auto-Precharge	H	H	L	H	L	H	BA	Column	H	Column	4)5)9)
No Operation	H	X	L	H	H	H	X	X	X	X	4)
Device Deselect	H	X	H	X	X	X	X	X	X	X	4)
Power Down Entry	H	L	H	X	X	X	X	X	X	X	4)10)
			L	H	H	H					
Power Down Exit	L	H	H	X	X	X	X	X	X	X	4)10)
			L	H	H	H					

1) The state of ODT does not affect the states described in this table. The ODT function is not available during Self Refresh.
2) “X” means H or L (but a defined logic level).
3) Operation that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.
4) All DDR2 SDRAM commands are defined by states of $\overline{CS}$, $\overline{WE}$, $\overline{RAS}$, $\overline{CAS}$ and CKE at the rising edge of the clock.
5) Bank addresses BA[2:0] determine which bank is to be operated upon. For (E)MRS BA[2:0] selects an (Extended) Mode Register.
6) All banks must be in a precharged idle state, CKE must be high at least for t_{XP} and all read/write bursts must be finished before the (Extended) Mode Register set Command is issued.
7) V_{REF} must be maintained during Self Refresh operation.
8) Self Refresh Exit is asynchronous.
9) Burst reads or writes at BL = 4 cannot be terminated.
10) The Power Down Mode does not perform any refresh operations. The duration of Power Down is therefore limited by the refresh requirements.

Table 16 - Clock Enable (CKE) Truth Table for Synchronous Transitions

Current State[1]	CKE		Command (N)[2][3] RAS, CAS, WE, CS	Action (N)[2]	Note[4][5]
	Previous Cycle[6] (N-1)	Current Cycle[6] (N)			
Power-Down	L	L	X	Maintain Power-Down	7)8)11)
	L	H	DESELECT or NOP	Power-Down Exit	7)9)10)11)
Self Refresh	L	L	X	Maintain Self Refresh	8)11)12)
	L	H	DESELECT or NOP	Self Refresh Exit	9)11)12)13)14)
Bank(s) Active	H	L	DESELECT or NOP	Active Power-Down Entry	7)9)10)11)15)
All Banks Idle	H	L	DESELECT or NOP	Precharge Power-Down Entry	7)9)10)11)15)
	H	L	AUTOREFRESH	Self Refresh Entry	7)11)14)16)
Any State other than listed above	H	H	Refer to the Command Truth Table		17)

1) Current state is the state of the DDR2 SDRAM immediately prior to clock edge N.
2) Command (N) is the command registered at clock edge N, and Action (N) is a result of Command (N).
3) The state of ODT does not affect the states described in this table. The ODT function is not available during Self Refresh. .
4) CKE must be maintained HIGH while the device is in OCD calibration mode.
5) Operation that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.
6) CKE (N) is the logic state of CKE at clock edge N; CKE (N-1) was the state of CKE at the previous clock edge.
7) The Power-Down Mode does not perform any refresh operations. The duration of Power-Down Mode is therefore limited by the refresh requirements.
8) "X" means "don't care (including floating around V_{REF})" in Self Refresh and Power Down. However ODT must be driven HIGH or LOW in Power Down if the ODT function is enabled (Bit A2 or A6 set to 1 in EMRS(1)).
9) All states and sequences not shown are illegal or reserved unless explicitly described elsewhere in this document.
10) Valid commands for Power-Down Entry and Exit are NOP and DESELECT only.
11) $t_{CKE.MIN}$ of 3 clocks means CKE must be registered on three consecutive positive clock edges. CKE must remain at the valid input level the entire time it takes to achieve the 3 clocks of registration. Thus, after any CKE transition, CKE may not transition from its valid level during the time period of $t_{IS} + 2 \times t_{CK} + t_{IH}$.
12) V_{REF} must be maintained during Self Refresh operation.
13) On Self Refresh Exit DESELECT or NOP commands must be issued on every clock edge occurring during the t_{XSNR} period. Read commands may be issued only after t_{XSRD} (200 clocks) is satisfied.
14) Valid commands for Self Refresh Exit are NOP and DESELCT only.
15) Power-Down and Self Refresh can not be entered while Read or Write operations, (Extended) mode Register operations, Precharge or Refresh operations are in progress.
16) Self Refresh mode can only be entered from the All Banks Idle state.
17) Must be a legal command as defined in the Command Truth Table.

Table 17 - Data Mask (DM) Truth Table

Name (Function)	DM	DQs	Note
Write Enable	L	Valid	1)
Write Inhibit	H	X	

1) Used to mask write data; provided coincident with the corresponding data.

5 Electrical Characteristics

This chapter describes the Electrical Characteristics.

5.1 Absolute Maximum Ratings

Caution is needed not to exceed absolute maximum ratings of the DRAM device listed in **Table 18** at any time.

Table 18 - Absolute Maximum Ratings

Symbol	Parameter	Rating		Unit	Note
		Min.	Max.		
V_{DD}	Voltage on V_{DD} pin relative to V_{SS}	–1.0	+2.3	V	1)
V_{DDQ}	Voltage on V_{DDQ} pin relative to V_{SS}	–0.5	+2.3	V	1)2)
V_{DDL}	Voltage on V_{DDL} pin relative to V_{SS}	–0.5	+2.3	V	1)2)
V_{IN}, V_{OUT}	Voltage on any pin relative to V_{SS}	–0.5	+2.3	V	1)3)
T_{STG}	Storage Temperature	–55	+150	°C	1)2)

1) When V_{DD} and V_{DDQ} and V_{DDL} are less than 500 mV; V_{REF} may be equal to or less than 300 mV. VDD and VDDQ must be within 300mv of each other at all times; and VREF must be not greater than 0.6 x VDDQ.
2) Storage Temperature is the case surface temperature on the center/top side of the DRAM.
3) Voltage on any input or I/O may not exceed voltage on VDDQ.

Attention: Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Table 19 - DRAM Component Operating Temperature Range

Symbol	Parameter	Rating		Unit	Note[1)-4)]
		Min.	Max.		
T_{OPER}	Operating Temperature	0	+95	°C	Commercial Temperature
		-40	+95	°C	Industrial Temperature
		-40	+105	°C	Automotive A2 Temperature
		-40	+95	°C	Automotive A3 Temperature
		-55	+125	°C	High-Rel Temperature

1) Operating Temperature is the case surface temperature on the center / top side of the DRAM.
2) The operating temperature range are the temperatures where all DRAM specification will be supported.
3) Above 105℃ the Auto-Refresh command interval has to be reduced to tREFI= 3.9 μ s.
4) when operating this product above 105℃, before the self refresh is entered, A7 bit of MR2 must be enabled.

5.2 DC Characteristics

Table 20 - Recommended DC Operating Conditions (SSTL_18)

Symbol	Parameter	Rating			Unit	Note
		Min.	Typ.	Max.		
V_{DD}	Supply Voltage	1.7	1.8	1.9	V	1)5)
V_{DDL}	Supply Voltage for DLL	1.7	1.8	1.9	V	1)
V_{DDQ}	Supply Voltage for Output	1.7	1.8	1.9	V	1)5)
V_{REF}	Input Reference Voltage	0.49 × V_{DDQ}	0.5 × V_{DDQ}	0.51 × V_{DDQ}	V	2)3)
V_{TT}	Termination Voltage	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V	4)

1) V_{DDQ} tracks with V_{DD}, V_{DDL} tracks with V_{DD}. AC parameters are measured with V_{DD}, V_{DDQ} and V_{DDL} tied together.
2) The value of V_{REF} may be selected by the user to provide optimum noise margin in the system. Typically the value of V_{REF} is expected to be about 0.5 × V_{DDQ} of the transmitting device and V_{REF} is expected to track variations in V_{DDQ}.
3) Peak to peak ac noise on V_{REF} may not exceed ±2% V_{REF} (dc)
4) V_{TT} is not applied directly to the device. V_{TT} is a system supply for signal termination resistors, is expected to be set equal to V_{REF}, and must track variations in die dc level of V_{REF}.
5) There is no specific device VDD supply voltage requirement for SSTL_18 compliance. However under all conditions VDDQ must be less than or equal to VDD.

Table 21 - ODT DC Electrical Characteristics

Parameter / Condition	Symbol	Min.	Nom.	Max.	Unit	Note
Termination resistor impedance value for EMRS(1)[A6,A2] = [0,1]; 75 Ohm	Rtt1(eff)	60	75	90	Ω	1)
Termination resistor impedance value for EMRS(1)[A6,A2] =[1,0]; 150 Ohm	Rtt2(eff)	120	150	180	Ω	1)
Termination resistor impedance value for EMRS(1)(A6,A2)=[1,1]; 50 Ohm	Rtt3(eff)	40	50	60	Ω	1)2)
Deviation of V_M with respect to V_{DDQ} / 2	delta V_M	–6.00	—	+ 6.00	%	3)

1) Measurement Definition for Rtt(eff): Apply $V_{IH(ac)}$ and $V_{IL(ac)}$ to test pin separately, then measure current I(V_{IHac}) and I(V_{ILac}) respectively. Rtt(eff) = ($V_{IH(ac)}$ – $V_{IL(ac)}$) /(I(V_{IHac}) – I(V_{ILac})).
2) Optional for DDR2-667, mandatory for DDR2-800.
3) Measurement Definition for VM: Turn ODT on and measure voltage (VM) at test pin (midpoint) with no load: delta V_M = ((2 x V_M / V_{DDQ}) – 1) x 100%

Table 22 - Input and Output Leakage Currents

Symbol	Parameter / Condition	Min.	Max.	Unit	Note
I_L	Input Leakage Current; any input 0 V < VIN < V_{DD}	–2	+2	µA	1)
I_{OZ}	Output Leakage Current; 0 V < VOUT < V_{DDQ}	–5	+5	µA	2)

1) All other pins not under test = 0 V
2) DQ's, LDQS, $\overline{\text{LDQS}}$, UDQS, $\overline{\text{UDQS}}$, DQS, $\overline{\text{DQS}}$, RDQS, $\overline{\text{RDQS}}$ are disabled and ODT is turned off

5.3 DC & AC Characteristics

DDR2 SDRAM pin timing are specified for either single ended or differential mode depending on the setting of the EMRS(1) "Enable $\overline{DQS}$" mode bit; timing advantagees of differential mode are realized in system design. The method by which the DDR2 SDRAM pin timing are measured is mode dependent. In single ended mode, timing relationships are measured relative to the rising or falling edges of DQS crossing at V_{REF}.

In differential mode, these timing relationships are measured relative to the crosspoint of DQS and its complement, $\overline{DQS}$. This distinction in timing methods is verified by design and characterization but not subject to production test. In single ended mode, the $\overline{DQS}$ (and $\overline{RDQS}$) signals are internally disabled and don't care.

Table 23 - DC & AC Logic Input Levels

Symbol	Parameter	DDR2-667, DDR2-800, DDR2-1066		Units
		Min.	Max.	
$V_{IH(dc)}$	DC input logic HIGH	V_{REF} + 0.125	V_{DDQ} + 0.3 1)	V
$V_{IL(dc)}$	DC input LOW	–0.3	V_{REF} – 0.125	V
$V_{IH(ac)}$	AC input logic HIGH	V_{REF} + 0.200	V_{DDQ} + V_{PEAK} 2)	V
$V_{IL(ac)}$	AC input LOW	V_{SSQ} – V_{PEAK} 2)	V_{REF} – 0.200	V

1) VDDQ + 300mV allowed provided 1.9V is not exceeded.
2) Refer to Overshoot/undershoot specification. for Vpeak value: maximum peak amplitude allowed for overshoot and undershoot.

Table 24 - Single-ended AC Input Test Conditions

Symbol	Condition	Value	Unit	Notes
V_{REF}	Input reference voltage	0.5 × V_{DDQ}	V	1)
$V_{SWING.MAX}$	Input signal maximum peak to peak swing	1.0	V	1)
SLEW	Input signal minimum Slew Rate	1.0	V / ns	2)3)

1) Input waveform timing is referenced to the input signal crossing through the V_{REF} level applied to the device under test.
2) The input signal minimum Slew Rate is to be maintained over the range from $V_{IH(ac).MIN}$ to V_{REF} for rising edges and the range from V_{REF} to $V_{IL(ac).MAX}$ for falling edges as shown in **Figure 3**.
3) AC timings are referenced with input waveforms switching from $V_{IL(ac)}$ to $V_{IH(ac)}$ on the positive transitions and $V_{IH(ac)}$ to $V_{IL(ac)}$ on the negative transitions.

Figure 3 - Single-ended AC Input Test Conditions Diagram

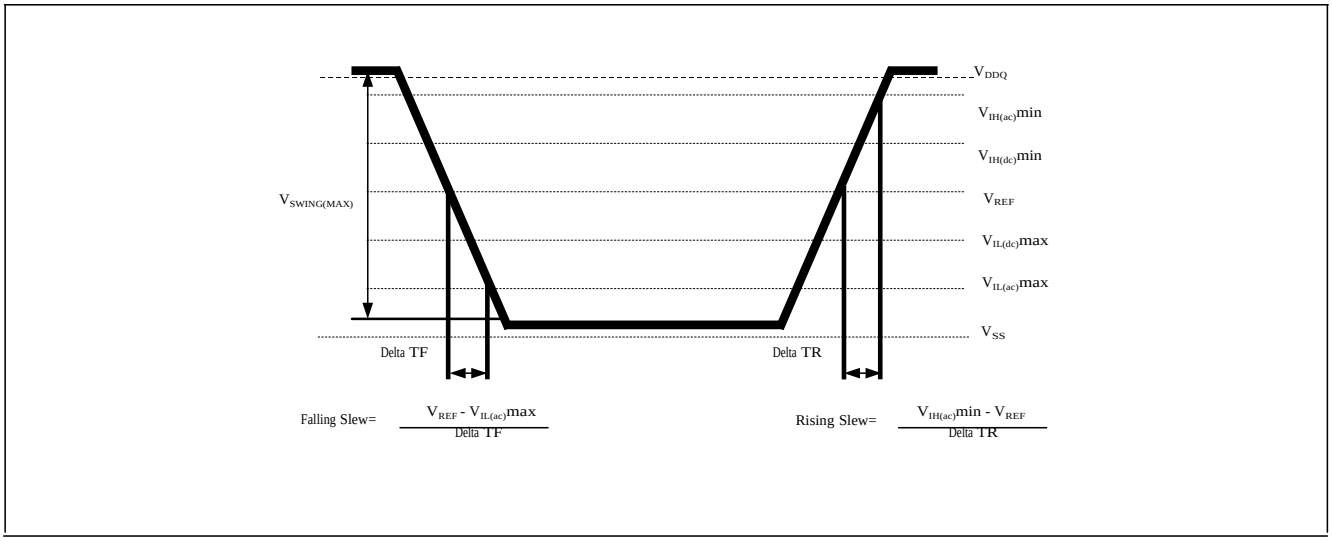
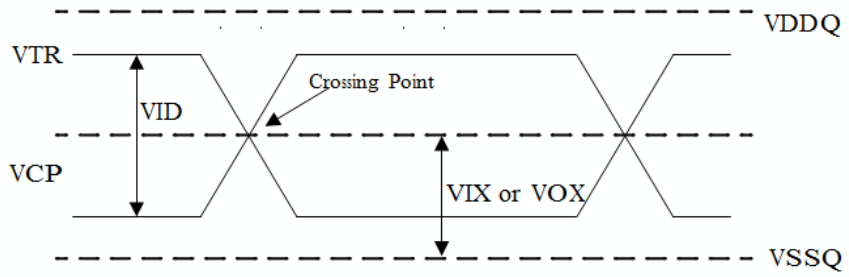


Table 25 - Differential DC and AC Input and Output Logic Levels

Symbol	Parameter	Min.	Max.	Unit	Notes
$V_{IN(dc)}$	DC input signal voltage	–0.3	V_{DDQ} + 0.3		1)6)
$V_{ID(dc)}$	DC differential input voltage	0.25	V_{DDQ} + 0.3		2)6)
$V_{ID(ac)}$	AC differential input voltage	0.5	V_{DDQ} + Vpeak	V	3)7)
$V_{IX(ac)}$	AC differential cross point input voltage	0.5 × V_{DDQ} – 0.175	0.5 × V_{DDQ} + 0.175	V	4)
$V_{OX(ac)}$	AC differential cross point output voltage	0.5 × V_{DDQ} – 0.125	0.5 × V_{DDQ} + 0.125	V	5)

1) $V_{IN(dc)}$ specifies the allowable DC execution of each input of differential pair such as CK, $\overline{CK}$, DQS, $\overline{DQS}$ etc.
2) $V_{ID(dc)}$ specifies the input differential voltage V_{TR}– V_{CP} required for switching. The minimum value is equal to $V_{IH(dc)}$ – $V_{IL(dc)}$.
3) $V_{ID(ac)}$ specifies the input differential voltage V_{TR} – V_{CP} required for switching. The minimum value is equal to $V_{IH(ac)}$ – $V_{IL(ac)}$.
4) The value of $V_{IX(ac)}$ is expected to equal 0.5 × V_{DDQ} of the transmitting device and $V_{IX(ac)}$ is expected to track variations in V_{DDQ}. $V_{IX(ac)}$ indicates the voltage at which differential input signals must cross.
5) The value of VOX(ac) is expected to equal 0.5 × VDDQ of the transmitting device and VOX(ac) is expected to track variations in VDDQ. VOX(ac) indicates the voltage at which differential input signals must cross.
6) VDDQ + 300mV allowed provided 1.9V is not exceeded.
7) Refer to Overshoot/undershoot specification. for Vpeak value: maximum peak amplitude allowed for overshoot and undershoot.

Figure 4 - Differential DC and AC Input and Output Logic Levels Diagram



5.4 Output Buffer Characteristics

This chapter describes the Output Buffer Characteristics.

Table 26 - SSTL_18 Output DC Current Drive

Symbol	Parameter	SSTL_18	Unit	Notes
I_{OH}	Output Minimum Source DC Current	-13.4	mA	1)2)4)
I_{OL}	Output Minimum Sink DC Current	13.4	mA	2)3)4)

1) V_{DDQ} = 1.7 V; V_{OUT} = 1.42 V. (V_{OUT}–V_{DDQ}) / I_{OH} must be less than 21 Ω for values of V_{OUT} between V_{DDQ} and V_{DDQ} – 280 mV.
2) The values of $I_{OH(dc)}$ and $I_{OL(dc)}$ are based on the conditions given in 1) and 3). They are used to test drive current capability to ensure $V_{IH.MIN}$ plus a noise margin and $V_{IL.MAX}$ minus a noise margin are delivered to an SSTL_18 receiver. The actual current values are derived by shifting the desired driver operating points along 21 Ohm load line to define a convenient current for measurement.
3) V_{DDQ} = 1.7 V; V_{OUT} = 280 mV. V_{OUT} / I_{OL} must be less than 21 Ohm for values of V_{OUT} between 0 V and 280 mV.
4) The dc value of V_{REF} applied to the receiving device is set V_{TT}.

Table 27 - SSTL_18 Output AC Test Conditions

Symbol	Parameter	SSTL_18	Unit	Note
V_{OTR}	Output Timing Measurement Reference Level	0.5 × V_{DDQ}	V	

Table 28 - OCD Default Characteristics

Symbol	Description	Min.	Nominal	Max.	Unit	Notes
—	Output Impedance	See full strength default driver characteristics			Ω	1)2)
—	Pull-up / Pull down mismatch	0	—	4	Ω	1)2)3)
—	Output Impedance step size for OCD calibration	0	—	1.5	Ω	4)
S_{OUT}	Output Slew Rate	1.5	—	5.0	V / ns	1)5)6)

1) V_{DDQ} = 1.8 V ± 0.1 V; V_{DD} = 1.8 V ± 0.1 V
2) Impedance measurement condition for output source dc current: V_{DDQ} = 1.7 V, V_{OUT} = 1420 mV; (V_{OUT}–V_{DDQ}) / I_{OH} must be less than 23.4 ohms for values of V_{OUT} between V_{DDQ} and V_{DDQ} – 280 mV. Impedance measurement condition for output sink dc current: V_{DDQ} = 1.7 V; V_{OUT} = –280 mV; V_{OUT} / I_{OL} must be less than 23.4 Ohms for values of V_{OUT} between 0 V and 280 mV.
3) Mismatch is absolute value between pull-up and pull-down, both measured at same temperature and voltage.
4) This represents the step size when the OCD is near 18 ohms at nominal conditions across all process parameters and represents only the DRAM uncertainty. A 0 Ohm value (no calibration) can only be achieved if the OCD impedance is 18 ± 0.75 Ohms under nominal conditions.
5) The absolute value of the Slew Rate as measured from DC to DC is equal to or greater than the Slew Rate as measured from AC to AC. This is verified by design and characterization but not subject to production test.
6) Timing skew due to DRAM output Slew Rate mis-match between DQS / $\overline{DQS}$ and associated DQ's is included in t_{DQSQ} and t_{QHS} specification.

5.5 Input / Output Capacitance

This chapter contains the Input / Output Capacitance.

Table 29 - Input / Output Capacitance

Symbol	Parameter	DDR2-667		DDR2-800		DDR2-1066		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
CCK	Input capacitance, CK and $\overline{CK}$	1.0	2.0	1.0	2.0	1.0	2.0	pF
CDCK	Input capacitance delta, CK and $\overline{CK}$	—	0.25	—	0.25	—	0.25	pF
CI	Input capacitance, all other input-only pins	1.0	2.0	1.0	1.75	1.0	1.75	pF
CDI	Input capacitance delta, all other input- only pins	—	0.25	—	0.25	—	0.25	pF
CIO	Input/output capacitance, DQ, DM, DQS, $\overline{DQS}$	2.5	3.5	2.5	3.5	2.5	3.5	pF
CDIO	Input/output capacitance delta, DQ, DM, DQS, $\overline{DQS}$	—	0.5	—	0.5	—	0.5	pF

5.6 Overshoot and Undershoot Specification

This chapter contains Overshoot and Undershoot Specification.

Table 30 - AC Overshoot / Undershoot Specification for Address and Control Pins

Parameter	DDR2-667	DDR2-800	DDR2-1066	Unit
Maximum peak amplitude allowed for overshoot area	0.5	0.5	0.5	V
Maximum peak amplitude allowed for undershoot area	0.5	0.5	0.5	V
Maximum overshoot area above V_{DD}	0.8	0.66	0.5	V-ns
Maximum undershoot area below V_{SS}	0.8	0.66	0.5	V-ns

Figure 5 - AC Overshoot / Undershoot Diagram for Address and Control Pins

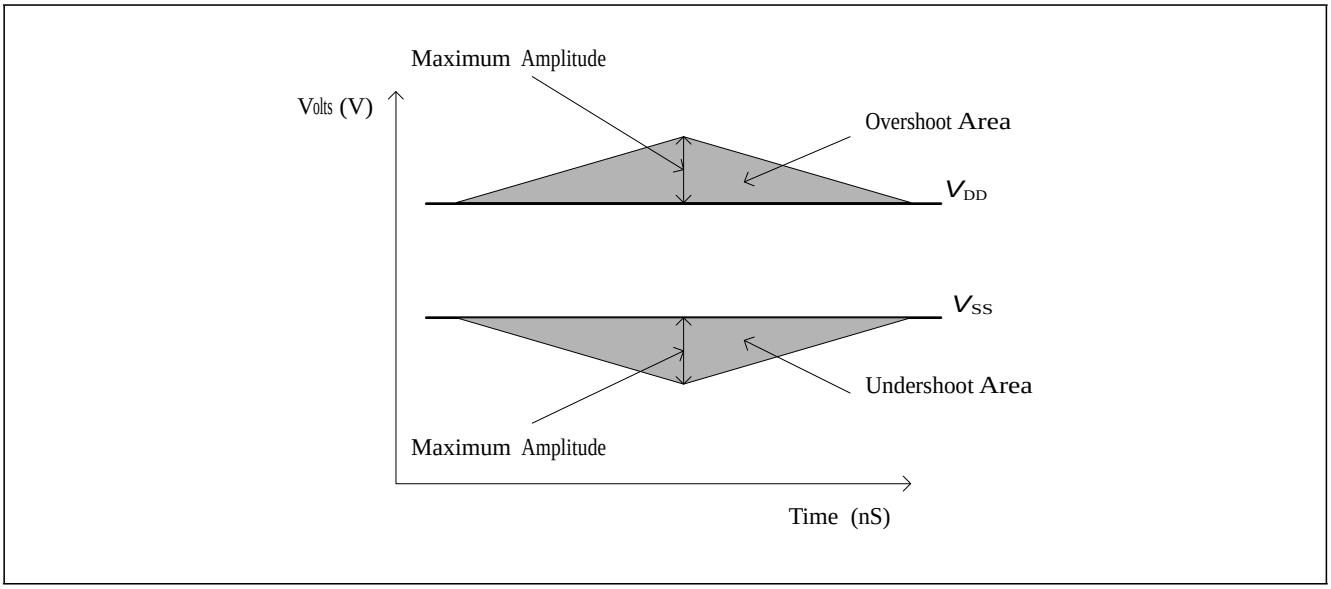
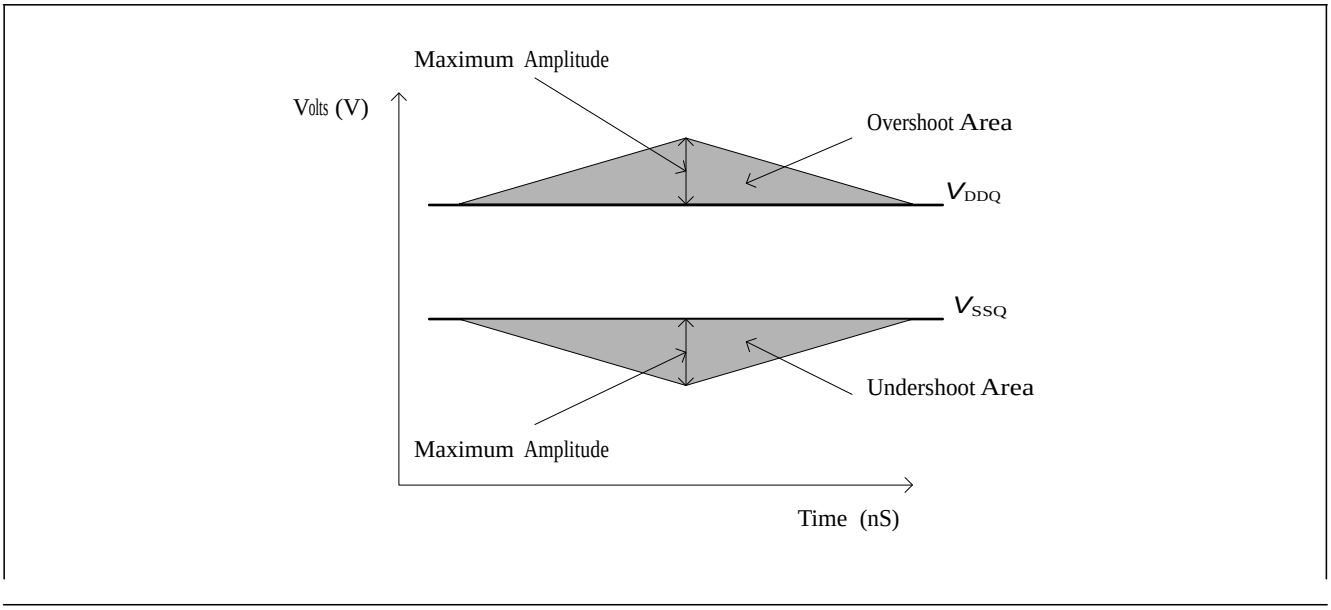


Table 31 - AC Overshoot / Undershoot Specification for Clock, Data, Strobe and Mask Pins

Parameter	DDR2-667	DDR2-800	DDR2-1066	Unit
Maximum peak amplitude allowed for overshoot area	0.5	0.5	0.5	V
Maximum peak amplitude allowed for undershoot area	0.5	0.5	0.5	V
Maximum overshoot area above V_{DDQ}	0.23	0.23	0.19	V-ns
Maximum undershoot area below V_{SSQ}	0.23	0.23	0.19	V-ns

Figure 6 - AC Overshoot / Undershoot Diagram for Clock, Data, Strobe and Mask Pins



6 Currents Measurement Conditions

This chapter describes the Current Measurement, Specifications and Conditions.

Table 32 - I_{DD} Measurement Conditions

Parameter	Symbol	Note[1)-7)]
Operating Current - One bank Active - Precharge $t_{CK} = t_{CK(IDD)}$, $t_{RC} = t_{RC(IDD)}$, $t_{RAS} = t_{RAS.MIN(IDD)}$, CKE is HIGH, $\overline{CS}$ is HIGH between valid commands. Address and control inputs are switching; Databus inputs are switching.	I_{DD0}	
Operating Current - One bank Active - Read - Precharge I_{OUT} = 0 mA, BL = 4, $t_{CK} = t_{CK(IDD)}$, $t_{RC} = t_{RC(IDD)}$, $t_{RAS} = t_{RAS.MIN(IDD)}$, $t_{RCD} = t_{RCD(IDD)}$, AL = 0, CL = CL(IDD); CKE is HIGH, $\overline{CS}$ is HIGH between valid commands. Address and control inputs are switching; Databus inputs are switching.	I_{DD1}	
Precharge Power-Down Current All banks idle; CKE is LOW; $t_{CK} = t_{CK(IDD)}$;Other control and address inputs are stable; Data bus inputs are floating.	I_{DD2P}	
Precharge Standby Current All banks idle; $\overline{CS}$ is HIGH; CKE is HIGH; $t_{CK} = t_{CK(IDD)}$; Other control and address inputs are switching, Data bus inputs are switching.	I_{DD2N}	
Precharge Quiet Standby Current All banks idle; $\overline{CS}$ is HIGH; CKE is HIGH; $t_{CK} = t_{CK(IDD)}$; Other control and address inputs are stable, Data bus inputs are floating.	I_{DD2Q}	
Active Power-Down Current All banks open; $t_{CK} = t_{CK(IDD)}$, CKE is LOW; Other control and address inputs are stable; Data bus inputs are floating. MRS A12 bit is set to 0 (Fast Power-down Exit).	$I_{DD3P(0)}$	
Active Power-Down Current All banks open; $t_{CK} = t_{CK(IDD)}$, CKE is LOW; Other control and address inputs are stable, Data bus inputs are floating. MRS A12 bit is set to 1 (Slow Power-down Exit);	$I_{DD3P(1)}$	
Active Standby Current All banks open; $t_{CK} = t_{CK(IDD)}$; $t_{RAS} = t_{RAS.MAX(IDD)}$, $t_{RP} = t_{RP(IDD)}$; CKE is HIGH, $\overline{CS}$ is HIGH between valid commands. Address inputs are switching; Data Bus inputs are switching;	I_{DD3N}	
Operating Current Burst Read: All banks open; Continuous burst reads; BL = 4; AL = 0, CL = $CL_{(IDD)}$; $t_{CK} = t_{CK(IDD)}$; $t_{RAS} = t_{RAS.MAX.(IDD)}$, $t_{RP} = t_{RP(IDD)}$; CKE is HIGH, CS is HIGH between valid commands. Address inputs are switching; Data Bus inputs are switching; I_{OUT} = 0 mA.	I_{DD4R}	
Operating Current Burst Write: All banks open; Continuous burst writes; BL = 4; AL = 0, CL = $CL_{(IDD)}$; $t_{CK} = t_{CK(IDD)}$; $t_{RAS} = t_{RAS.MAX(IDD)}$, $t_{RP} = t_{RP(IDD)}$; CKE is HIGH, CS is HIGH between valid commands. Address inputs are switching; Data Bus inputs are switching;	I_{DD4W}	
Burst Refresh Current $t_{CK} = t_{CK(IDD)}$, Refresh command every $t_{RFC} = t_{RFC(IDD)}$ interval, CKE is HIGH, CS is HIGH between valid commands, Other control and address inputs are switching, Data bus inputs are switching.	I_{DD5B}	
Distributed Refresh Current $t_{CK} = t_{CK(IDD)}$, Refresh command every t_{REFI} = 7.8 µs interval, CKE is LOW and CS is HIGH between valid commands, Other control and address inputs are switching, Data bus inputs are switching.	I_{DD5D}	

Parameter	Symbol	Note
Self-Refresh Current CKE ≤ 0.2 V; external clock off, CK and $\overline{CK}$ at 0 V; Other control and address inputs are floating, Data bus inputs are floating.	I_{DD6}	
Operating Bank Interleave Read Current 1. All banks interleaving reads, I_{OUT} = 0 mA; BL = 4, CL = $CL_{(IDD)}$, AL = $t_{RCD(IDD)}$ -1 × $t_{CK(IDD)}$; t_{CK} = $t_{CK(IDD)}$, t_{RC} = $t_{RC(IDD)}$, t_{RRD} = $t_{RRD(IDD)}$; tFAW = tFAW(IDD), Trcd = 1 x tck(IDD); CKE is HIGH, CS is HIGH between valid commands. Address bus inputs are stable during deselects; Data bus is switching. 2. Timing pattern: see **Detailed I_{DD7}** timings shown below.	I_{DD7}	

1) V_{DDQ} = 1.8 V ± 0.1 V; V_{DD} = 1.8 V ± 0.1 V.
2) I_{DD} specifications are tested after the device is properly initialized.
3) I_{DD} parameter are specified with ODT disabled.
4) Data Bus consists of DQ, DM, DQS, $\overline{DQS}$, RDQS, $\overline{RDQS}$, LDQS, $\overline{LDQS}$, UDQS and $\overline{UDQS}$. IDD values must be met with all combinations of EMRS bits 10 and 11.
5) Definitions for I_{DD} , see **Table 33**.
6) Timing parameter minimum and maximum values for I_{DD} current measurements are defined in Chapter 7.
7) Input slew rate is specified by AC Parametric Test Condition.

Detailed I_{DD7}

The detailed timings are shown below for IDD7. Changes will be required if timing parameter changes are made to the specification. Legend: A = Active; RA = Read with Autoprecharge; D = Deselect.

I_{DD7} : Operating Current: All Bank Interleave Read operation

All banks are being interleaved at minimum $t_{RC.IDD}$ without violating $t_{RRD.IDD}$ and $t_{FAW.IDD}$ using a burst length of 4. Control and address bus inputs are STABLE during DESELECTs. IOUT = 0 mA.

Timing Patterns for devices with 1KB page size

DDR2-667: A0 RA0 D A1 RA1 D A2 RA2 D A3 RA3 D D A4 RA4 D A5 RA5 D A6 RA6 D A7 RA7 D D
DDR2-800: A0 RA0 D A1 RA1 D A2 RA2 D A3 RA3 D D D A4 RA4 D A5 RA5 D A6 RA6 D A7 RA7 D D D
DDR2-1066: A0 RA0 D D A1 RA1 D D A2 RA2 D D A3 RA3 D D D D D A4 RA4 D D A5 RA5 D D A6 RA6
D D A7 RA7 D D D D D

Timing Patterns for devices with 2KB page size

DDR2-667: A0 RA0 D D A1 RA1 D D A2 RA2 D D A3 RA3 D D D A4 RA4 D D A5 RA5 D D A6 RA6 D D A7 RA7 D D D
DDR2-800: A0 RA0 D D A1 RA1 D D A2 RA2 D D A3 RA3 D D D D A4 RA4 D D A5 RA5 D D A6 RA6 D D A7 RA7 D D D D
DDR2-1066: A0 RA0 D D D D A1 RA1 D D D D A2 RA2 D D D D A3 RA3 D D D D A4 RA4 D D D D A5 RA5 D D D D A6
RA6 D D D D A7 RA7 D D D D

Table 33 - Definition for I_{DD}

Parameter	Description
LOW	Defined as $V_{IN} \leq V_{IL.AC.MAX}$
HIGH	Defined as $V_{IN} \geq V_{IH.AC.MIN}$
STABLE	Defined as inputs are stable at a HIGH or LOW level
FLOATING	Defined as inputs are $V_{REF} = V_{DDQ} / 2$
SWITCHING	Defined as: Inputs are changing between high and low every other clock (once per two clocks) for address and control signals, and inputs changing between high and low every other clock (once per clock) for DQ signals not including mask or strobes

Table 34 - I_{DD} Specification

Symbol	-3D			-25D/-25E			-19F			Unit	Note[1)]
	DDR2 - 667			DDR2 - 800			DDR2 - 1066				
	Max.			Max.			Max.				
	95℃[2)]	105℃[2)]	125℃[2)]	95℃[2)]	105℃[2)]	125℃[2)]	95℃[2)]	105℃[2)]	125℃[2)]		
IDD0	60	65	65	65	70	75	70	75	80	mA	×8
IDD0	75	80	85	80	85	90	85	90	95	mA	×16
IDD1	70	75	80	75	80	85	80	85	90	mA	×8
IDD1	95	100	105	100	105	110	105	110	115	mA	×16
IDD2P	12	15	18	12	15	18	12	15	18	mA	×8
IDD2P	12	15	18	12	15	18	12	15	18	mA	×16
IDD2N	40	45	50	45	50	55	50	55	60	mA	×8
IDD2N	40	45	50	45	50	55	50	55	60	mA	×16
IDD2Q	40	45	50	45	50	55	50	55	60	mA	×8
IDD2Q	40	45	50	45	50	55	50	55	60	mA	×16
IDD3N	50	55	60	55	60	65	60	65	70	mA	x8
IDD3N	55	60	70	60	70	75	65	75	80	mA	x16
IDD3PF	21	28	30	25	32	35	25	32	40	mA	x8
IDD3PF	26	33	40	32	40	45	32	40	45	mA	x16
IDD3PS	23	29	30	27	33	35	27	33	40	mA	x8
IDD3PS	28	34	40	34	40	45	34	40	45	mA	x16
IDD4R	140	140	150	160	160	170	190	190	200	mA	×8
IDD4R	190	190	200	220	220	230	260	260	270	mA	×16
IDD4W	140	140	150	160	160	170	190	190	200	mA	×8
IDD4W	190	190	200	220	220	230	260	260	270	mA	×16
IDD5B	140	140	145	145	145	150	150	150	155	mA	x8
IDD5B	145	145	150	150	150	155	155	155	160	mA	x16
IDD5D	14	17	20	14	17	20	14	17	20	mA	x8
IDD5D	14	17	20	14	17	20	14	17	20	mA	x16
IDD6	14	17	20	14	17	20	14	17	20	mA	x8
IDD6	14	17	20	14	17	20	14	17	20	mA	x16
IDD7	150	155	160	170	175	180	180	180	190	mA	×8
IDD7	220	230	250	240	250	270	250	250	280	mA	×16

1) This version IDD value just for reference
2) Tcase temperature.

7 Timing Characteristics

This chapter contains speed grade definition, AC timing parameter and ODT tables.

7.1 Speed Grade Definitions

Table 35 - Speed Grade Definition

Speed Grade			DDR2–1066		DDR2–800		Unit	Note
UniIC Sort Name			–19F		–25D			
CAS-RCD-RP latencies			7–7–7		5–5–5		t_{CK}	
Parameter		Symbol	Min.	Max.	Min.	Max.	—	
Clock Period	@ CL = 4	t_{CK}	3.75	7.5	3.75	8	ns	
	@ CL = 5	t_{CK}	3	7.5	2.5	8	ns	
	@ CL = 6	t_{CK}	2.5	7.5	—	—	ns	
	@ CL = 7	t_{CK}	1.875	7.5	—	—	ns	
Row Active Time		t_{RAS}	45	70k	45	70k	ns	
Row Cycle Time		t_{RC}	58.125	—	57.5	—	ns	
RAS-CAS-Delay		t_{RCD}	13.125	—	12.5	—	ns	
Row Precharge Time		t_{RP}	13.125	—	12.5	—	ns	

Table 36 - Speed Grade Definition

Speed Grade			DDR2–800		DDR2–667		Unit	Note
UniIC Sort Name			–25E		–3D			
CAS-RCD-RP latencies			6–6–6		5–5–5		t_{CK}	
Parameter		Symbol	Min.	Max.	Min.	Max.	—	
Clock Period	@ CL = 4	t_{CK}	3.75	8	3.75	8	ns	
	@ CL = 5	t_{CK}	3	8	3	8	ns	
	@ CL = 6	t_{CK}	2.5	8	—	—	ns	
Row Active Time		t_{RAS}	45	70k	45	70k	ns	
Row Cycle Time		t_{RC}	60	—	60	—	ns	
RAS-CAS-Delay		t_{RCD}	15	—	15	—	ns	
Row Precharge Time		t_{RP}[1)]	15	—	15	—	ns	

1) 8 bank device Precharge All Allowance : tRPall for a Precharge All command for an 8 Bank device is equal to tRP + 1 x tCK, where tRP is the value for a single bank precharge, which are shown in this table.

7.2 Component AC Timing Parameters

Table 37 - DRAM Component Timing Parameter by Speed Grade - DDR2–800, DDR2–667, DDR3-1066

Parameter	Symbol	DDR2–1066		DDR2–800		DDR2–667		Unit	Note[1) -7)]
		Min.	Max.	Min.	Max.	Min.	Max.		
DQ output access time from CK / $\overline{CK}$	t_{AC}	-350	350	–400	+400	–450	+450	ps	8)
$\overline{CAS}$ to $\overline{CAS}$ command delay	t_{CCD}	2	—	2		2	—	nCK	
Average clock high pulse width	$t_{CH.AVG}$	0.48	0.52	0.48	0.52	0.48	0.52	$t_{CK.AVG}$	9)10)
Average clock period	$t_{CK.AVG}$	1875	7500	2500	8000	3000	8000	ps	9)10)
CKE minimum pulse width (high and low pulse width)	t_{CKE}	3	—	3	—	3	—	nCK	11)
Average clock low pulse width	$t_{CL.AVG}$	0.48	0.52	0.48	0.52	0.48	0.52	$t_{CK.AVG}$	9)10)
Auto-Precharge write recovery + precharge time	t_{DAL}	WR + t_{nRP}	—	WR + t_{nRP}	—	WR + t_{nRP}	—	nCK	12)13)
Minimum time clocks remain ON after CKE asynchronously drops LOW	t_{DELAY}	t_{IS} + $t_{CK .AVG}$ + t_{IH}	—	t_{IS} + $t_{CK .AVG}$ + t_{IH}	—	t_{IS} + $t_{CK .AVG}$ + t_{IH}	—	ns	
DQ and DM input hold time	$t_{DH.BASE}$	75	—	125	—	175	—	ps	14)18)19)
DQ and DM input pulse width for each input	t_{DIPW}	0.35	—	0.35	—	0.35	—	$t_{CK.AVG}$	
DQS output access time from CK / $\overline{CK}$	t_{DQSCK}	-325	325	–350	+350	–400	+400	ps	8)
DQS input high pulse width	t_{DQSH}	0.35	—	0.35	—	0.35	—	$t_{CK.AVG}$	
DQS input low pulse width	t_{DQSL}	0.35	—	0.35	—	0.35	—	$t_{CK.AVG}$	
DQS-DQ skew for DQS & associated DQ signals	t_{DQSQ}	—	175	—	200	—	240	ps	15)
DQS latching rising transition to associated clock edges	t_{DQSS}	– 0.25	+ 0.25	– 0.25	+ 0.25	– 0.25	+ 0.25	$t_{CK.AVG}$	16)
DQ and DM input setup time	$t_{DS.BASE}$	0	—	50	—	100	—	ps	17)18)19)
DQS falling edge hold time from CK	t_{DSH}	0.2	—	0.2	—	0.2	—	$t_{CK.AVG}$	16)
DQS falling edge to CK setup time	t_{DSS}	0.2	—	0.2	—	0.2	—	$t_{CK.AVG}$	16)
Four Activate Window for 1KB page size products	t_{FAW}	35	—	35	—	37.5	—	ns	34)
Four Activate Window for 2KB page size products	t_{FAW}	45	—	45	—	50	—	ns	34)
CK half pulse width	t_{HP}	Min($t_{CH.ABS}$,	—	Min($t_{CH.ABS}$,	—	Min($t_{CH.ABS}$,	—	ps	20)
Data-out high-impedance time from CK / $\overline{CK}$	t_{HZ}	—	$t_{AC.MAX}$	—	$t_{AC.MAX}$	—	$t_{AC.MAX}$	ps	8)21)
Address and control input hold time	$t_{IH.BASE}$	200	—	250	—	275	—	ps	22)24)
Control & address input pulse width for each input	t_{IPW}	0.6	—	0.6	—	0.6	—	$t_{CK.AVG}$	
Address and control input setup time	$t_{IS.BASE}$	125	—	175	—	200	—	ps	23)24)

Parameter	Symbol	DDR2–1066		DDR2–800		DDR2–667		Unit	Note[1)-7)]
		Min.	Max.	Min.	Max.	Min.	Max.		
DQ low impedance time from CK/CK	$t_{LZ.DQ}$	2 × $t_{AC.MIN}$	$t_{AC.MAX}$	2 × $t_{AC.MIN}$	$t_{AC.MAX}$	2 × $t_{AC.MIN}$	$t_{AC.MAX}$	ps	8)21)
DQS/DQS low-impedance time from CK / CK	$t_{LZ.DQS}$	$t_{AC.MIN}$	$t_{AC.MAX}$	$t_{AC.MIN}$	$t_{AC.MAX}$	$t_{AC.MIN}$	$t_{AC.MAX}$	ps	8)21)
MRS command to ODT update delay	t_{MOD}	0	12	0	12	0	12	ns	34)
Mode register set command cycle time	t_{MRD}	2	—	2	—	2	—	nCK	
OCD drive mode output delay	t_{OIT}	0	12	0	12	0	12	ns	34)
DQ/DQS output hold time from DQS	t_{QH}	t_{HP} – t_{QHS}	—	t_{HP} – t_{QHS}	—	t_{HP} – t_{QHS}	—	ps	25)
DQ hold skew factor	t_{QHS}	—	250	—	300	—	340	ps	26)
Average periodic refresh Interval	t_{REFI}	—	7.8	—	7.8	—	7.8	µs	27)28)
		—	3.9	—	3.9	—	3.9	µs	27)29)
Auto-Refresh to Active/Auto-Refresh command period	t_{RFC}	105	—	105	—	105	—	ns	30)
Read preamble	t_{RPRE}	0.9	1.1	0.9	1.1	0.9	1.1	$t_{CK.AVG}$	31)32)
Read postamble	t_{RPST}	0.4	0.6	0.4	0.6	0.4	0.6	$t_{CK.AVG}$	31)33)
Active to active command period for 1KB page size products	t_{RRD}	7.5	—	7.5	—	7.5	—	ns	34)
Active to active command period for 2KB page size products	t_{RRD}	10	—	10	—	10	—	ns	34)
Internal Read to Precharge command delay	t_{RTP}	7.5	—	7.5	—	7.5	—	ns	34)
Write preamble	t_{WPRE}	0.35	—	0.35	—	0.35	—	$t_{CK.AVG}$	
Write postamble	t_{WPST}	0.4	0.6	0.4	0.6	0.4	0.6	$t_{CK.AVG}$	36)
Write recovery time	t_{WR}	15	—	15	—	15	—	ns	34)
Internal write to read command delay	t_{WTR}	7.5	—	7.5	—	7.5	—	ns	34)35)
Exit active power down to read command	t_{XARD}	3	—	2	—	2	—	nCK	37)
Exit active power down to read command (slow exit, lower power)	t_{XARDS}	10 – AL	—	8 – AL	—	7 – AL	—	nCK	
Exit precharge power-down to any command	t_{XP}	3	—	2	—	2	—	nCK	
Exit self-refresh to a non-read command	t_{XSNR}	t_{RFC} +10	—	t_{RFC} +10	—	t_{RFC} +10	—	ns	34)
Exit self-refresh to read command	t_{XSRD}	200	—	200	—	200	—	nCK	
Write command to DQS associated clock edges	WL	RL – 1		RL – 1		RL–1		nCK	

1) V_{DDQ} = 1.8 V ± 0.1V; V_{DD} = 1.8 V ± 0.1 V.
2) Timing that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.
3) Timings are guaranteed with CK/$\overline{CK}$ differential Slew Rate of 2.0 V/ns. For DQS signals timings are guaranteed with a differential Slew Rate of 2.0 V/ns in differential strobe mode and a Slew Rate of 1 V/ns in single ended mode.
4) The CK / $\overline{CK}$ input reference level (for timing reference to CK / $\overline{CK}$) is the point at which CK and $\overline{CK}$ cross. The DQS / $\overline{DQS}$, RDQS / $\overline{RDQS}$, input reference level is the crosspoint when in differential strobe mode.

5) Inputs are not recognized as valid until V_{REF} stabilizes. During the period before V_{REF} stabilizes, CKE = 0.2 x V_{DDQ} is recognized as low.
6) The output timing reference voltage level is V_{TT}.
7) New units, '$t_{CK.AVG}$' and 'nCK', are introduced in DDR2–667, DDR2–800 and DDR2-1066. Unit '$t_{CK.AVG}$' represents the actual $t_{CK.AVG}$ of the input clock under operation. Unit 'nCK' represents one clock cycle of the input clock, counting the actual clock edges. Note that in DDR2–400 and DDR2–533, 't_{CK}' is used for both concepts. Example: t_{XP} = 2 [nCK] means; if Power Down exit is registered at Tm, an Active command may be registered at Tm + 2, even if (Tm + 2 - Tm) is 2 x $t_{CK.AVG}$ + $t_{ERR.2PER(Min)}$.
8) When the device is operated with input clock jitter, this parameter needs to be derated by the actual $t_{ERR(6\text{-}10per)}$ of the input clock. (output deratings are relative to the SDRAM input clock.) For example, if the measured jitter into a DDR2–667 SDRAM has $t_{ERR(6\text{-}10PER).MIN}$ = – 272 ps and $t_{ERR(6-\ 10PER).MAX}$ = + 293 ps, then $t_{DQSCK.MIN(DERATED)}$ = $t_{DQSCK.MIN}$ – $t_{ERR(6\text{-}10PER).MAX}$ = – 400 ps – 293 ps = – 693 ps and $t_{DQSCK.MAX(DERATED)}$ = $t_{DQSCK.MAX}$ – $t_{ERR(6\text{-}10PER).MIN}$ = 400 ps + 272 ps = + 672 ps. Similarly, $t_{LZ.DQ}$ for DDR2–667 derates to $t_{LZ.DQ.MIN(DERATED)}$ = - 900 ps – 293 ps = – 1193 ps and $t_{LZ.DQ.MAX(DERATED)}$ = 450 ps + 272 ps = + 722 ps. (Caution on the MIN/MAX usage!)
9) Input clock jitter spec parameter. These parameters and the ones in **Chapter 7.3** are referred to as 'input clock jitter spec parameters. The jitter specified is a random jitter meeting a Gaussian distribution.
10) These parameters are specified per their average values, however it is understood that the relationship as defined in **Chapter 7.3** between the average timing and the absolute instantaneous timing holds all the times (min. and max of SPEC values are to be used for calculations of **Chapter 7.3**).
11) $t_{CKE.MIN}$ of 3 clocks means CKE must be registered on three consecutive positive clock edges. CKE must remain at the valid input level the entire time it takes to achieve the 3 clocks of registration. Thus, after any CKE transition, CKE may not transition from its valid level during the time period of t_{IS} + 2 x t_{CK} + t_{IH}.
12) DAL = WR + RU{t_{RP}(ns) / t_{CK}(ns)}, where RU stands for round up. WR refers to the tWR parameter stored in the MRS. For t_{RP}, if the result of the division is not already an integer, round up to the next highest integer. t_{CK} refers to the application clock period.
13) $t_{DAL.nCK}$ = WR [nCK] + $t_{nRP.nCK}$ = WR + RU{t_{RP} [ps] / $t_{CK.AVG}$[ps] }, where WR is the value programmed in the EMR.
14) Input waveform timing t_{DH} with differential data strobe enabled MR[bit10] = 0, is referenced from the differential data strobe crosspoint to the input signal crossing at the $V_{IH.DC}$ level for a falling signal and from the differential data strobe crosspoint to the input signal crossing at the $V_{IL.DC}$ level for a rising signal applied to the device under test. DQS, $\overline{DQS}$ signals must be monotonic between $V_{IL.DC.MAX}$ and $V_{IH.DC.MIN}$. See **Figure 8**.
15) t_{DQSQ}: Consists of data pin skew and output pattern effects, and p-channel to n-channel variation of the output drivers as well as output slew rate mismatch between DQS / $\overline{DQS}$ and associated DQ in any given cycle.
16) These parameters are measured from a data strobe signal ((L/U/R)DQS / $\overline{DQS}$) crossing to its respective clock signal (CK / $\overline{CK}$) crossing. The spec values are not affected by the amount of clock jitter applied (i.e. $t_{JIT.PER}$, $t_{JIT.CC}$, etc.), as these are relative to the clock signal crossing. That is, these parameters should be met whether clock jitter is present or not.
17) Input waveform timing t_{DS} with differential data strobe enabled MR[bit10] = 0, is referenced from the input signal crossing at the $V_{IH.AC}$ level to the differential data strobe crosspoint for a rising signal, and from the input signal crossing at the $V_{IL.AC}$ level to the differential data strobe crosspoint for a falling signal applied to the device under test. DQS, $\overline{DQS}$ signals must be monotonic between $V_{il(DC)MAX}$ and $V_{ih(DC)MIN}$. See **Figure 8**.
18) If t_{DS} or t_{DH} is violated, data corruption may occur and the data must be re-written with valid data before a valid READ can be executed.
19) These parameters are measured from a data signal ((L/U)DM, (L/U)DQ0, (L/U)DQ1, etc.) transition edge to its respective data strobe signal ((L/U/R)DQS / $\overline{DQS}$) crossing.
20) t_{HP} is the minimum of the absolute half period of the actual input clock. t_{HP} is an input parameter but not an input specification parameter. It is used in conjunction with t_{QHS} to derive the DRAM output timing t_{QH}. The value to be used for t_{QH} calculation is determined by the following equation; t_{HP} = MIN ($t_{CH.ABS}$, $t_{CL.ABS}$), where, $t_{CH.ABS}$ is the minimum of the actual instantaneous clock high time; $t_{CL.ABS}$ is the minimum of the actual instantaneous clock low time.
21) t_{HZ} and t_{LZ} transitions occur in the same access time as valid data transitions. These parameters are referenced to a specific voltage level which specifies when the device output is no longer driving (t_{HZ}), or begins driving (t_{LZ}) .
22) input waveform timing is referenced from the input signal crossing at the $V_{IL.DC}$ level for a rising signal and $V_{IH.DC}$ for a falling signal applied to the device under test. See **Figure 9**
23) Input waveform timing is referenced from the input signal crossing at the $V_{IH.AC}$ level for a rising signal and $V_{IL.AC}$ for a falling signal applied to the device under test. See **Figure 9**.
24) These parameters are measured from a command/address signal (CKE, CS, RAS, CAS, WE, ODT, BA0, A0, A1, etc.) transition edge to its respective clock signal (CK / $\overline{CK}$) crossing. The spec values are not affected by the amount of clock jitter applied (i.e. $t_{JIT.PER}$, $t_{JIT.CC}$, etc.), as the setup and hold are relative to the clock signal crossing that latches the command/address. That is, these parameters should be met whether clock jitter is present or not.
25) t_{QH} = t_{HP} – t_{QHS}, where: t_{HP} is the minimum of the absolute half period of the actual input clock; and t_{QHS} is the specification value under the max column. {The less half-pulse width distortion present, the larger the t_{QH} value is; and the larger the valid data eye will be.} Examples: 1) If the system provides t_{HP} of 1315 ps into a DDR2–667 SDRAM, the DRAM provides t_{QH} of 975 ps minimum. 2) If the system provides t_{HP} of 1420 ps into a DDR2–667 SDRAM, the DRAM provides t_{QH} of 1080 ps minimum.
26) t_{QHS} accounts for: 1) The pulse duration distortion of on-chip clock circuits, which represents how well the actual t_{HP} at the input is transferred to the output; and 2) The worst case push-out of DQS on one transition followed by the worst case pull-in of DQ on the next transition, both of which are independent of each other, due to data pin skew, output pattern effects, and pchannel to n-channel variation of the output drivers.
27) The Auto-Refresh command interval has be reduced to 3.9 µs when operating the DDR2 DRAM in a temperature range between 105 ℃ and 125 ℃.

28) - 40 °C≤ T_{CASE} ≤ 105 ℃.
29) 105 ℃ < T_{CASE} ≤ 125 ℃.
30) A maximum of eight Refresh commands can be posted to any given DDR2 SDRAM, meaning that the maximum absolute interval between any Refresh command and the next Refresh command is 9 x t_{REFI}.
31) t_{RPST} end point and t_{RPRE} begin point are not referenced to a specific voltage level but specify when the device output is no longer driving (t_{RPST}), or begins driving (t_{RPRE}). **Figure 7** shows a method to calculate these points when the device is no longer driving (t_{RPST}), or begins driving (t_{RPRE}) by measuring the signal at two different voltages. The actual voltage measurement points are not critical as long as the calculation is consistent.
32) When the device is operated with input clock jitter, this parameter needs to be derated by the actual $t_{JIT.PER}$ of the input clock. (output deratings are relative to the SDRAM input clock.) For example, if the measured jitter into a DDR2–667 SDRAM has $t_{JIT.PER.MIN}$ = – 72 ps and $t_{JIT.PER.MAX}$ = + 93 ps, then $t_{RPRE.MIN(DERATED)}$ = $t_{RPRE.MIN}$ + $t_{JIT.PER.MIN}$ = 0.9 x $t_{CK.AVG}$ – 72 ps = + 2178 ps and $t_{RPRE.MAX(DERATED)}$ = $t_{RPRE.MAX}$ + $t_{JIT.PER.MAX}$ = 1.1 x $t_{CK.AVG}$ + 93 ps = + 2843 ps. (Caution on the MIN/MAX usage!).
33) When the device is operated with input clock jitter, this parameter needs to be derated by the actual $t_{JIT.DUTY}$ of the input clock. (output deratings are relative to the SDRAM input clock.) For example, if the measured jitter into a DDR2–667 SDRAM has $t_{JIT.DUTY.MIN}$ = – 72 ps and $t_{JIT.DUTY.MAX}$ = + 93 ps, then $t_{RPST.MIN(DERATED)}$ = $t_{RPST.MIN}$ + $t_{JIT.DUTY.MIN}$ = 0.4 x $t_{CK.AVG}$ – 72 ps = + 928 ps and $t_{RPST.MAX(DERATED)}$ = $t_{RPST.MAX}$ + $t_{JIT.DUTY.MAX}$ = 0.6 x $t_{CK.AVG}$ + 93 ps = + 1592 ps. (Caution on the MIN/MAX usage!).
34) For these parameters, the DDR2 SDRAM device is characterized and verified to support t_{nPARAM} = RU{t_{PARAM} / $t_{CK.AVG}$}, which is in clock cycles, assuming all input clock jitter specifications are satisfied. For example, the device will support t_{nRP} = RU{t_{RP} / $t_{CK.AVG}$}, which is in clock cycles, if all input clock jitter specifications are met. This means: For DDR2–667 5–5–5, of which t_{RP} = 15 ns, the device will support t_{nRP} = RU{t_{RP} / $t_{CK.AVG}$} = 5, i.e. as long as the input clock jitter specifications are met, Precharge command at Tm and Active command at Tm + 5 is valid even if (Tm + 5 - Tm) is less than 15 ns due to input clock jitter.
35) t_{WTR} is at lease two clocks (2 x t_{CK}) independent of operation frequency.
36) The maximum limit for this parameter is not a device limit. The device will operate with a greater value for this parameter, but system performance (bus turnaround) will degrade accordingly.
37) User can choose which active power down exit timing to use via MRS (bit 12). tXARD is expected to be used for fast active power down exit timing. tXARDS is expected to be used for slow active power down exit timing.

Figure 7 - Method for Calculating Transitions and Endpoint

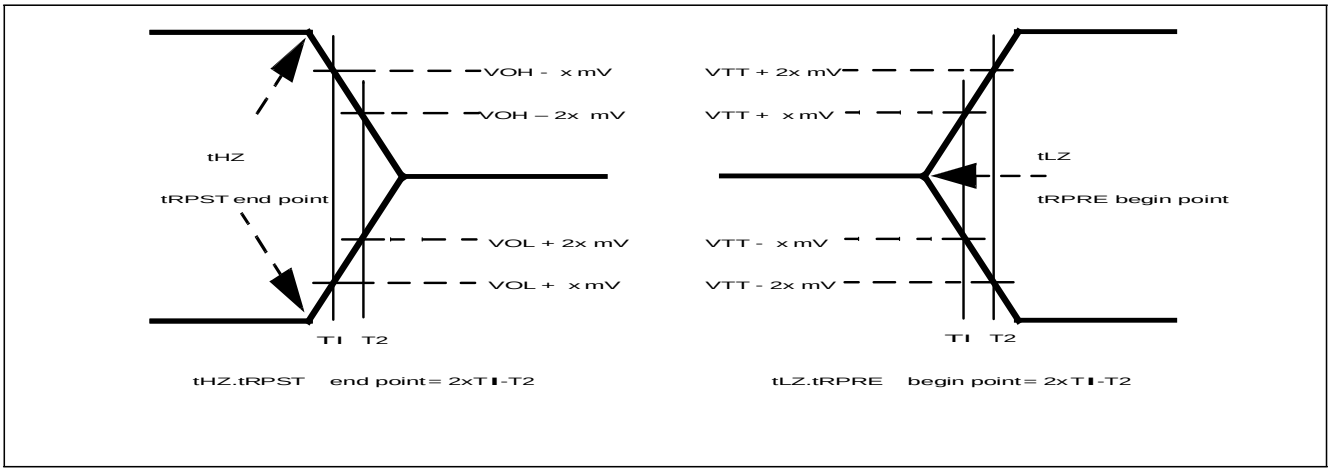


Figure 8 - Differential Input Waveform Timing - t_{DS} and t_{DH}

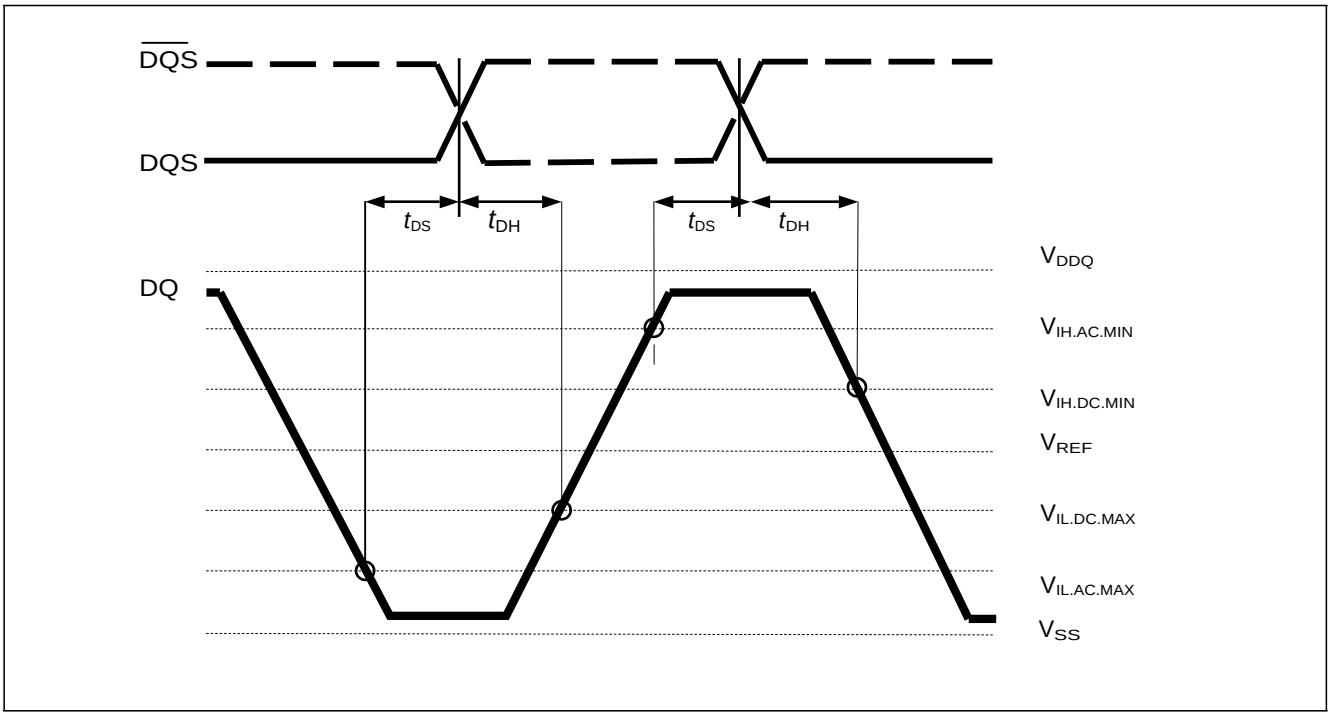
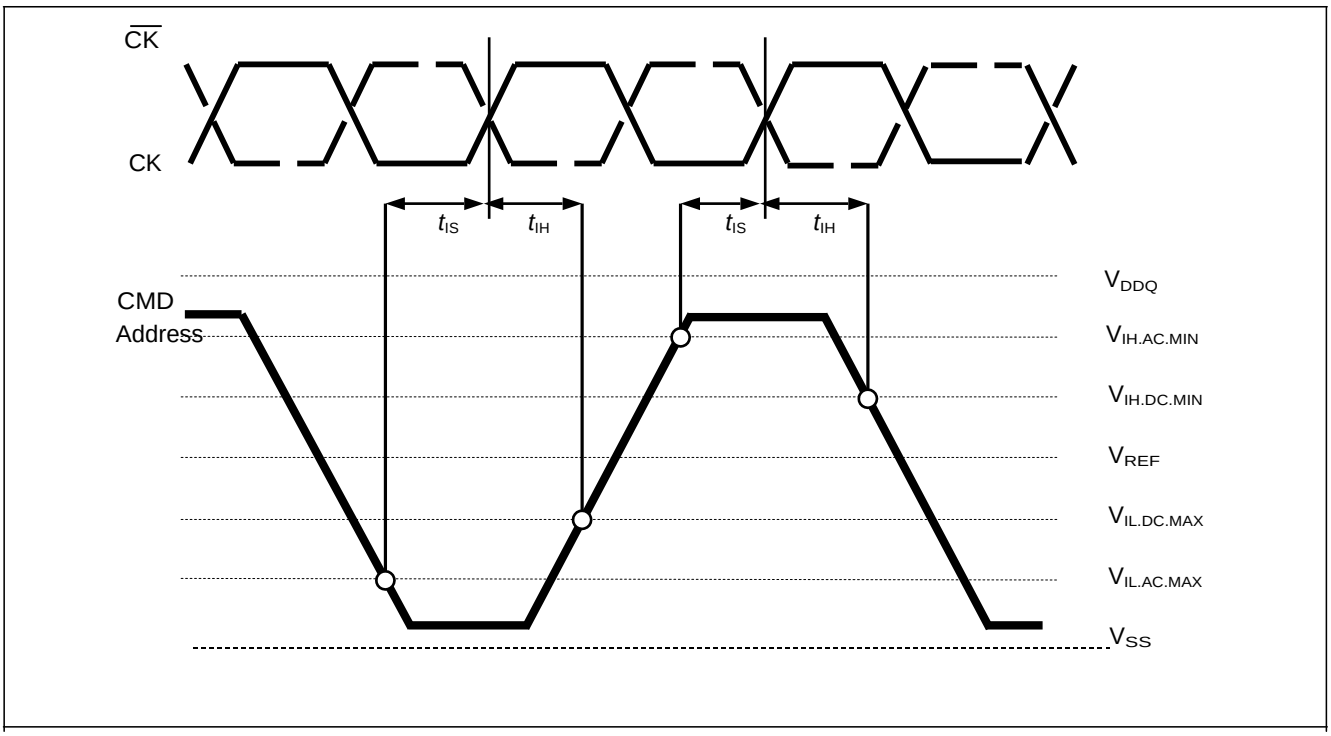


Figure 9 - Differential Input Waveform Timing - t_{IS} and t_{IH}



7.3 Jitter Definition and Clock Jitter Specification

Generally, jitter is defined as “the short-term variation of a signal with respect to its ideal position in time”. The following table provides an overview of the terminology.

Table 38 - Average Clock and Jitter Symbols and Definition

Symbol	Parameter	Description	Units
$t_{CK.AVG}$	Average clock period	$t_{CK.AVG}$ is calculated as the average clock period within any consecutive 200-cycle window: $tCK.AVG = \frac{1}{N} \cdot \sum_{j=1}^{N} tCK_j$ N = 200	ps
$t_{JIT.PER}$	Clock-period jitter	$t_{JIT.PER}$ is defined as the largest deviation of any single t_{CK} from $t_{CK.AVG}$: $t_{JIT.PER}$ = Min/Max of $\{t_{CKi} - t_{CK.AVG}\}$ where i = 1 to 200 $t_{JIT.PER}$ defines the single-period jitter when the DLL is already locked. $t_{JIT.PER}$ is not guaranteed through final production testing.	ps
t_{JIT}(PER, LCK)	Clock-period jitter during DLL-locking period	t_{JIT}(PER,LCK) uses the same definition as $t_{JIT.PER}$, during the DLL-locking period only. t_{JIT}(PER,LCK) is not guaranteed through final production testing.	ps
$t_{JIT.CC}$	Cycle-to-cycle clock period jitter	$t_{JIT.CC}$ is defined as the absolute difference in clock period between two consecutive clock cycles: $t_{JIT.CC}$ = Max of ABS$\{t_{CKi+1} - t_{CKi}\}$ $t_{JIT.CC}$ defines the cycle - to - cycle jitter when the DLL is already locked. $t_{JIT.CC}$ is not guaranteed through final production testing.	ps
t_{JIT}(CC, LCK)	Cycle-to-cycle clock period jitter during DLL-locking period	t_{JIT}(CC,LCK) uses the same definition as $t_{JIT.CC}$ during the DLL-locking period only. t_{JIT}(CC,LCK) is not guaranteed through final production testing.	ps
$t_{ERR.2PER}$	Cumulative error across 2 cycles	$t_{ERR.2PER}$ is defined as the cumulative error across 2 consecutive cycles from $t_{CK.AVG}$: $tERR\,2per = \sum_{j=i}^{i+n-1} tCK_j - n \cdot tCK\,avg$ n = 2 for t_{ERR}(2per) where i = 1 to 200	ps

Symbol	Parameter	Description	Units
$t_{ERR.nPER}$	Cumulative error across n cycles	$t_{ERR.2PER}$ is defined as the cumulative error across n consecutive cycles from $t_{CK.AVG}$: $tERR\ nper = \sum_{j=i}^{i+n-1} tCK_j - n\ tCK\ avg$ where, i = 1 to 200 and n = 3 for $t_{ERR.3PER}$ n = 4 for $t_{ERR.4PER}$ n = 5 for $t_{ERR.5PER}$ $6 \le n \le 10$ for $t_{ERR.6-10PER}$ $11 \le n \le 50$ for $t_{ERR.11-50PER}$	ps
$t_{CH.AVG}$	Average high-pulse width	$t_{CH.AVG}$ is defined as the average high-pulse width, as calculated across any consecutive 200 high pulses: $tCH(avg) = \frac{1}{(N \times tCk(avg))} \cdot \left(\sum_{j=1}^{N} tCH_j \right)$ N = 200	$t_{CK.AVG}$
$t_{CL.AVG}$	Average low-pulse width	$t_{CL.AVG}$ is defined as the average low-pulse width, as calculated across any consecutive 200 low pulses: $tCL(avg) = \frac{1}{(N \times tCk(avg))} \cdot \left(\sum_{j=1}^{N} tCL_j \right)$ N = 200	$t_{CK.AVG}$
$t_{JIT.DUTY}$	Duty-cycle jitter	$t_{JIT.DUTY}$ = Min/Max of {$t_{JIT.CH}$, $t_{JIT.CL}$}, where: $t_{JIT.CH}$ is the largest deviation of any single t_{CH} from $t_{CH.AVG}$ $t_{JIT.CL}$ is the largest deviation of any single t_{CL} from $t_{CL.AVG}$ $t_{JIT.CH}$ = {t_{CHi} - $t_{CH.AVG}$ × $t_{CK.AVG}$} where i=1 to 200 $t_{JIT.CL}$ = {t_{CLi} - $t_{CL.AVG}$ × $t_{CK.AVG}$} where i=1 to 200	ps

The following parameters are specified per their average values however, it is understood that the following relationship between the average timing and the absolute instantaneous timing holds all the time.

Table 39 - Absolute Jitter Value Definitions

Symbol	Parameter	Min.	Max.	Unit
$t_{CK.ABS}$	Clock period	$t_{CK.AVG(Min)}$ + $t_{JIT.PER(Min)}$	$t_{CK.AVG(Max)}$ + $t_{JIT.PER(Max)}$	ps
$t_{CH.ABS}$	Clock high-pulse width	$t_{CH.AVG(Min)}$ x $t_{CK.AVG(Min)}$ + $t_{JIT.DUTY(Min)}$	$t_{CH.AVG(Max)}$ x $t_{CK.AVG(Max)}$ + $t_{JIT.DUTY(Max)}$	ps
$t_{CL.ABS}$	Clock low-pulse width	$t_{CL.AVG(Min)}$ x $t_{CK.AVG(Min)}$ + $t_{JIT.DUTY(Min)}$	$t_{CL.AVG(Max)}$ x $t_{CK.AVG(Max)}$ + $t_{JIT.DUTY(Max)}$	ps

Example: for DDR2-667, $t_{CH.ABS.MIN}$ = (0.48 x 3000ps) – 125 ps = 1315 ps = 0.438 x 3000 ps.

Table 40 shows clock-jitter specifications.

Table 40 - Clock-Jitter Specifications for –667, –800,-1066

Symbol	Parameter	DDR2 -667		DDR2 -800		DDR-1066		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
$t_{CK.AVG}$	Average clock period nominal w/o jitter	3000	8000	2500	8000	1875	7500	ps
$t_{JIT.PER}$	Clock-period jitter	–125	125	–100	100	-90	90	ps
$t_{JIT(PER,LCK)}$	Clock-period jitter during DLL locking period	–100	100	–80	80	-80	80	ps
$t_{JIT.CC}$	Cycle-to-cycle clock-period jitter	–250	250	–200	200	-180	180	ps
$t_{JIT(CC,LCK)}$	Cycle-to-cycle clock-period jitter during DLL-locking	–200	200	–160	160	-160	160	ps
$t_{ERR.2PER}$	Cumulative error across 2 cycles	–175	175	–150	150	-132	132	ps
$t_{ERR.3PER}$	Cumulative error across 3 cycles	–225	225	–175	175	-157	157	ps
$t_{ERR.4PER}$	Cumulative error across 4 cycles	–250	250	–200	200	-175	175	ps
$t_{ERR.5PER}$	Cumulative error across 5 cycles	–250	250	–200	200	-188	188	ps
$t_{ERR(6-10PER)}$	Cumulative error across n cycles with n = 6 .. 10,	–350	350	–300	300	-250	250	ps
$t_{ERR(11-50PER)}$	Cumulative error across n cycles with n = 11 .. 50,	–450	450	–450	450	-425	425	ps
$t_{CH.AVG}$	Average high-pulse width	0.48	0.52	0.48	0.52	0.48	0.52	$t_{CK.AVG}$
$t_{CL.AVG}$	Average low-pulse width	0.48	0.52	0.48	0.52	0.48	0.52	$t_{CK.AVG}$
$t_{JIT.DUTY}$	Duty-cycle jitter	–125	125	–100	100	-75	75	ps

7.4 ODT AC Electrical Characteristics

This chapter describes the ODT AC electrical characteristics.

Table 41 - ODT AC Characteristics and Operating Conditions for DDR2-667 , DDR2-800, DDR-1066

Symbol	Parameter / Condition	DDR-667, DDR-800		DDR-1066		Unit	Note
		Min.	Max.	Min.	Max.		
t_{AOND}	ODT turn-on delay	2	2	2	2	n_{CK}	1)
t_{AON}	ODT turn-on	$t_{AC.MIN}$	$t_{AC.MAX}$ + 0.7 ns	$t_{AC.MIN}$	$t_{AC.MAX}$ + 2.575	ns	1)2)
t_{AONPD}	ODT turn-on (Power-Down Modes)	$t_{AC.MIN}$ + 2 ns	2 t_{CK} + $t_{AC.MAX}$ + 1 ns	$t_{AC.MIN}$ + 2 ns	3 t_{CK} + $t_{AC.MAX}$ + 1 ns	ns	1)
t_{AOFD}	ODT turn-off delay	2.5	2.5	2.5	2.5	n_{CK}	1)
t_{AOF}	ODT turn-off	$t_{AC.MIN}$	$t_{AC.MAX}$ + 0.6 ns	$t_{AC.MIN}$	$t_{AC.MAX}$ + 0.6 ns	ns	1)3)
t_{AOFPD}	ODT turn-off (Power-Down Modes)	$t_{AC.MIN}$ + 2 ns	2.5 t_{CK} + $t_{AC.MAX}$ + 1 ns	$t_{AC.MIN}$ + 2 ns	2.5 t_{CK} + $t_{AC.MAX}$ + 1 ns	ns	1)
t_{ANPD}	ODT to Power Down Mode Entry Latency	3	—	4	—	n_{CK}	1)
t_{AXPD}	ODT Power Down Exit Latency	8	—	11	—	n_{CK}	1)

1) New units, "$t_{CK.AVG}$" and "n_{CK}", are introduced in DDR2-667, DDR2-800 and DDR2-1066. Unit "$t_{CK.AVG}$" represents the actual $t_{CK.AVG}$ of the input clock under operation. Unit "n_{CK}" represents one clock cycle of the input clock, counting the actual clock edges. Note that in DDR2-400 and DDR2-533, "t_{CK}" is used for both concepts. Example: t_{XP} = 2 [n_{CK}] means; if Power Down exit is registered at T_m, an Active command may be registered at T_m + 2, even if (T_m + 2 - T_m) is 2 x $t_{CK.AVG}$ + $t_{ERR.2PER(Min)}$.

2) ODT turn on time min is when the device leaves high impedance and ODT resistance begins to turn on. ODT turn on time max is when the ODT resistance is fully on. Both are measured from t_{AOND}, which is interpreted differently per speed bin. For DDR2-667/800 t_{AOND} is 2 clock cycles after the clock edge that registered a first ODT HIGH counting the actual input clock edges.

3) ODT turn off time min is when the device starts to turn off ODT resistance. ODT turn off time max is when the bus is in high impedance. Both are measured from t_{AOFD}, which is interpreted differently per speed bin. For DDR2-667/800, if $t_{CK(avg)}$ = 3 ns is assumed, t_{AOFD} is 1.5 ns (= 0.5 x 3 ns) after the second trailing clock edge counting from the clock edge that registered a first ODT LOW and by counting the actual input clock edges.

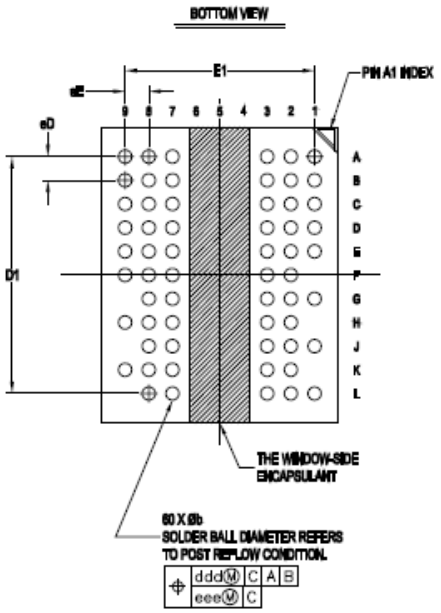
8 Package Outline

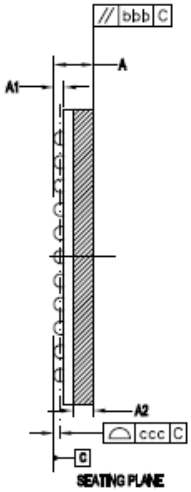
This chapter contains the package dimension figures.

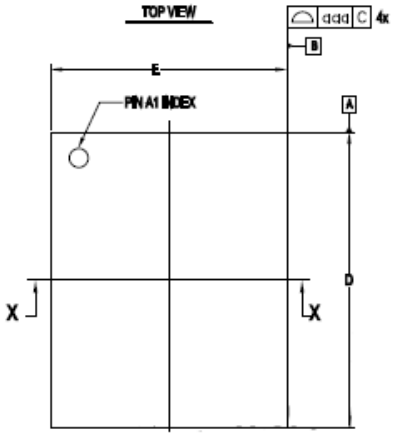
Notes

1. *Drawing according to ISO 8015*
2. *Dimensions in mm*
3. *General tolerances +/- 0.17*

Figure 10 - Package Outline PG-TFBGA-60



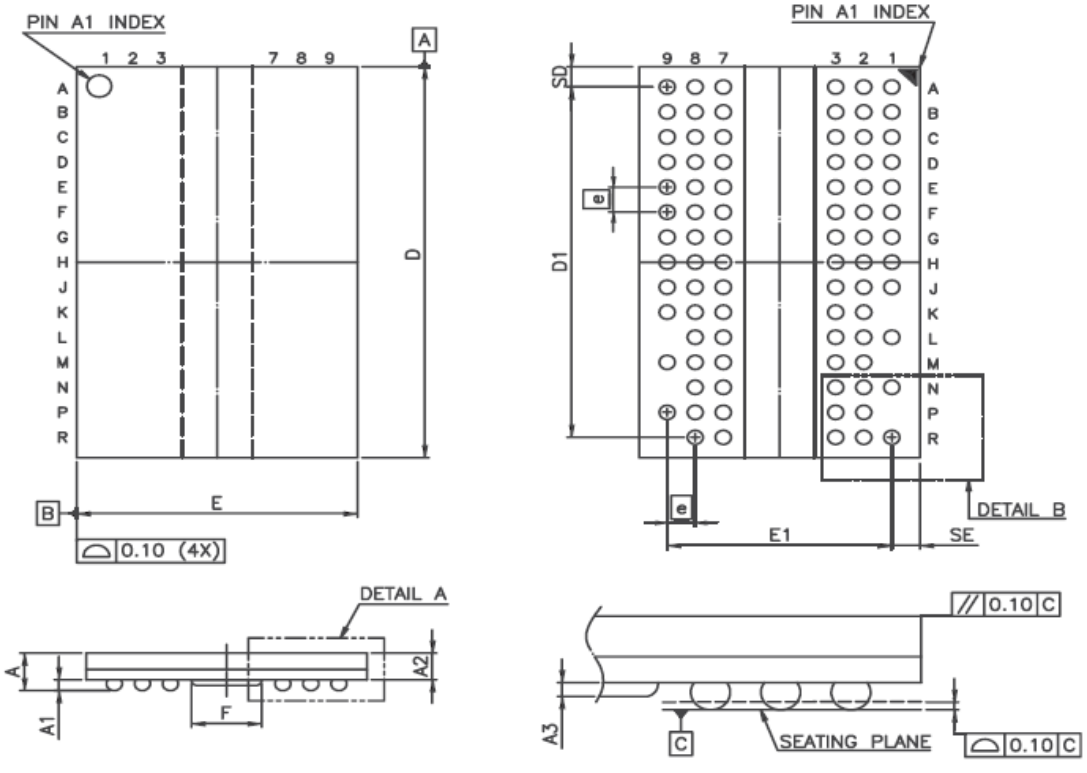




DIMENSION REFERENCES Units mm

REF.	MIN.	NOM.	MAX.
A	---	1.10	1.20
A1	0.25	0.35	0.40
A2	0.50	0.53	0.56
b	0.40	0.45	0.50
D	9.90	10.00	10.10
E	7.90	8.00	8.10
D1		8.00 BSC	
E1		6.40 BSC	
eE		0.80 BSC	
eD		0.80 BSC	
aaa	---	---	0.15
bbb	---	---	0.20
ccc	---	---	0.10
ddd	---	---	0.15
eee	---	---	0.08
t	---	0.17	0.20

Figure 11 - Package Outline PG-TFBGA-84



SYM.	DIMENSION (mm)			DIMENSION (inch)		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A	—	—	1.20	—	—	0.047
A1	0.30	0.35	0.40	0.012	0.014	0.016
A2	—	—	0.84	—	—	0.033
A3	0.10	0.15	0.20	0.004	0.006	0.008
b	0.40	0.45	0.50	0.016	0.018	0.020
D	12.40	12.50	12.60	0.488	0.492	0.496
D1	11.20 BSC			0.441 BSC		
E	7.90	8.00	8.10	0.311	0.315	0.319
E1	6.40 BSC			0.252 BSC		
F	2.00 BSC			0.079 BSC		
SD	0.65 BSC			0.026 BSC		
SE	0.80 BSC			0.031 BSC		
e	0.80 BSC			0.031 BSC		

9 Product Nomenclature

For reference the UniIC SDRAM component nomenclature is enclosed in this chapter.

Table 42 - Examples for Nomenclature Fields

Example for	Field Number										
	1	2	3	4	5	6	7	8	9	10	11
DDR2 SDRAM	SCB	18	T	512	80	0	A	F	–	25D	I

Table 43 - DDR2 Memory Components

Field	Description	Values	Coding
1	UniIC Component Prefix	SCE	UniIC ECC Memory components
		SCB	UniIC Commercial Memory components
2	Interface Voltage [V]	18	SSTL_18, + 1.8 V (± 0.1 V)
		15	SSTL_15, + 1.5 V (± 0.1 V)
3	DRAM Technology	T	DDR2
4	Component Density [Mbit]	32	32 Mbit
		64	64 Mbit
		128	128 Mbit
		256	256 Mbit
		512	512 Mbit
		1G	1 Gbit
		2G	2 Gbit
		4G	4 Gbit
5	Number of I/Os	40	× 4
		80	× 8
		16	× 16
6	Product Variant	0 .. 9	–
7	Die Revision	A	First
		B	Second
		C	Third
8	Package, Lead-Free Status	C	FBGA, lead-containing
		F	FBGA, lead-free
9	Power	–	Standard power product
		L	Low power product
10	Speed Grade	–19E	DDR2–1066 6–6–6
		–19F	DDR2–1066 7–7–7
		–25D	DDR2–800 5–5–5
		–25E	DDR2–800 6–6–6
		–3D	DDR2–667 5–5–5

Field	Description	Values	Coding
11	Temperature range	Blank	Commercial temperature range: 0 °C to 95 °C
		I	Industrial temperature range: -40 °C to 95 °C
		A2	Automotive temperature range, A2: -40 °C to 105 °C
		A3	Automotive temperature range, A3: -40 °C to 95 °C
		X	High-Rel temperature range: -55 °C to 125 °C

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